



HUAKE TESTING

FCC Test Report

Report Reference No.: HK2502080452-11E

FCC ID.: 2BDI3-K

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Date of issue.....: Apr. 10, 2025

Testing Laboratory Name: Shenzhen HUAKE Testing Technology Co., Ltd.

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Heping, Fuhai Street, Bao'an District, Shenzhen, Guangdong, China

Applicant's name: Shenzhen Haimeilan Technology Co., LTD.

Address: 9V777, East 9th Floor, Building 2, SEG Science Park, Huaqiang
North Street, Futian District, Shenzhen, 518000 China

Test specification

Standard: FCC CFR Title 47 Part 2, Part 27

TRF Originator.....: Shenzhen HUAKE Testing Technology Co., Ltd.

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Test item description: Smart Phone

Trade Mark: N/A

Manufacturer.....: Shenzhen Haimeilan Technology Co., LTD.

Model/Type reference.....: S25 Ultra

Series Models: F5 Pro, M13, F50 Pro, M5S Pro, F5, Note12 Pro, X40 Pro, X40
Edge, Mate 14, Mate 16, Mate 17, Mate 18, Mate 19, Mate 20, Mate
21, Mate 22, Mate 23, Mate 24, Mate 25, Mate 26, Mate 27,
Mate28, D14, D16, D17, D18, D19, D20, D21, D22, D23, D24, D25,
D26, D27, D28, D29, R12 pro, P5 pro, E50 Ultra, I16 pro max, P6
pro, Sp20 Pro, OP12 pro, T3 Pro, P8 Pro

Modulation Type: QPSK, 16QAM

Rating: DC5V from Type-C or DC3.85V from battery

Hardware version: V2.0

Software version.....: V2.0

Result.....: PASS

TEST REPORT

Test Report No.:	HK2502080452-11E	Apr. 10, 2025
		Date of issue

Equipment under Test : Smart Phone

Model /Type : S25 Ultra

Series Models : F5 Pro, M13, F50 Pro, M5S Pro, F5, Note12 Pro, X40 Pro, X40 Edge, Mate 14, Mate 16, Mate 17, Mate 18, Mate 19, Mate 20, Mate 21, Mate 22, Mate 23, Mate 24, Mate 25, Mate 26, Mate 27, Mate28, D14, D16, D17, D18, D19, D20, D21, D22, D23, D24, D25, D26, D27, D28, D29, R12 pro, P5 pro, E50 Ultra, I16 pro max, P6 pro, Sp20 Pro, OP12 pro, T3 Pro, P8 Pro

Applicant : **Shenzhen Haimeilan Technology Co., LTD.**

Address : 9V777, East 9th Floor, Building 2, SEG Science Park, Huaqiang North Street, Futian District, Shenzhen, 518000 China

Manufacturer : **Shenzhen Haimeilan Technology Co., LTD.**

Address : 9V777, East 9th Floor, Building 2, SEG Science Park, Huaqiang North Street, Futian District, Shenzhen, 518000 China

Test Result:	PASS
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The test report merely corresponds to the test sample.
It is not permitted to copy extracts of these test result without the written permission of the test laboratory.

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**** Modified History ****

Revision	Description	Issued Data	Remark
Revision 1.0	Initial Test Report Release	Apr. 10, 2025	Jason Zhou

1 Test Standards

The tests were performed according to following standards:

[FCC Part 2](#):Frequency Alloca-Tions And Radio Treaty Mat-Ters; General Rules And Reg-Ulations

[FCC Part 27](#):Miscellaneous Wireless Communications Services

[ANSI/TIA-603-E-2016](#): Land Mobile FM or PM Communications Equipment Measurement and Performance Standards.

[ANSI C63.26-2015](#): IEEE/ANSI Standard for Compliance Testing of Transmitters Used in Licensed Radio Services

[KDB971168 D01:v03r01](#) Measurement Guidance For Certification Of Licensed Digital Transmitters.

2 Summary

2.1 General Remarks

Date of receipt of test sample	:	Feb. 08, 2025
Testing commenced on	:	Feb. 08, 2025
Testing concluded on	:	Apr. 10, 2025

2.2 Product Description

The **Shenzhen Haimeilan Technology Co., LTD.**'s Model: S25 Ultra or the "EUT" as referred to in this report; more general information as follows, for more details, refer to the user's manual of the EUT.

Name of EUT	Smart Phone
Model/Type reference:	S25 Ultra
Series Models:	F5 Pro, M13, F50 Pro, M5S Pro, F5, Note12 Pro, X40 Pro, X40 Edge, Mate 14, Mate 16, Mate 17, Mate 18, Mate 19, Mate 20, Mate 21, Mate 22, Mate 23, Mate 24, Mate 25, Mate 26, Mate 27, Mate28, D14, D16, D17, D18, D19, D20, D21, D22, D23, D24, D25, D26, D27, D28, D29, R12 pro, P5 pro, E50 Ultra, I16 pro max, P6 pro, Sp20 Pro, OP12 pro, T3 Pro, P8 Pro
Model Difference:	All model's the function, software and electric circuit are the same, only with appearance, product color and model named different. Test sample model: S25 Ultra.
Power supply:	DC5V from Type-C or DC3.85V from battery
Adapter Information	DC5V from Type-C or DC3.85V from battery
Modulation Type	QPSK, 16QAM
Antenna Type	FPC Antenna
Antenna Gain	0.9dBi
Operation Frequency Band	LTE Band 7
Operation frequency	LTE Band 7: 2500 to 2570 MHz
LTE Release	R8
Extreme temp. Tolerance	-30°C to +50°C
Extreme vol. Limits	4.25VDC to 5.75VDC (nominal: 5.0VDC)

2.3 Equipment under Test

Power supply system utilised

Power supply voltage	:	☐ 120V/ 60 Hz	☐ 115V/60Hz
		☐ 12 V DC	☐ 24 V DC
		☒ Other (specified in blank below)	

DC5V from Type-C or DC3.85V from battery

2.4 Short description of the Equipment under Test (EUT)

2.4.1 GeneralDescription

S25 Ultra is subscriber equipment in the LTE system. LTE frequencyband is band 41; The Smart Phone implements suchfunctions as RF signal receiving/ transmitting, LTE protocol processing, voice, video MMS service, etc. Externally itprovides micro SD card interface, earphone port (to provide voice service) and SIM car dinterface.

2.5 Normal Accessory setting

Fully charged battery was used during the test.

2.6 EUT configuration

The following peripheral devices and interface cables were connected during the measurement:

● - supplied by the manufacturer

○ - supplied by the lab

○	Power Cable	Length (m) :	/
		Shield :	/
		Detachable :	/
○	Multimeter	Manufacturer :	/
		Model No. :	/

2.7 Related Submittal(s) / Grant (s)

This submittal(s) (test report) is intended forFCC ID: 2BDI3-K filing to comply with FCC Part 27, Rules.

2.8 Modifications

No modifications were implemented to meet testing criteria.

2.9 GeneralTest Conditions/Configurations

2.9.1 TestEnvironment

EnvironmentParameter	SelectedValuesDuringTests	
Relative Humidity	Ambient	
Temperature	TN	Ambient
Voltage	VL	4.25V
	VN	5.0V
	VH	5.75V

NOTE:VL=lowerextreme testvoltageVN=nominalvoltage
VH=upperextreme testvoltageTN=normaltemperature

3 Test Environment

3.1 Information of the Test Laboratory

Shenzhen HUAKE Testing Technology Co., Ltd.
 Add.: 1-2/F., Building B2, Junfeng Zhongcheng Zhizao Innovation Park, Heping,
 Fuhai Street, Bao'an District, Shenzhen, Guangdong, China

Testing Laboratory Authorization:

A2LA Accreditation Code is 4781.01.
 FCC Designation Number is CN1229.
 Canada IC CAB identifier is CN0045.
 CNAS Registration Number is L9589.

3.2 Test Description

Test Item	FCCRuleNo.	Verdict
Effective(Isotropic)RadiatedOutputPower	Part 2.1046 27.50(h)(2)	Pass
Peak-AverageRatio	Part 2.1046	Pass
ModulationCharacteristics	§2.1047	N/A
Bandwidth	Part 2.1049	Pass
BandEdgesCompliance	Part 2.1051 27.53(m)	Pass
SpuriousEmissionatAntennaTerminals	Part 2.1051 27.53(m)	Pass
Field Strengthof Spurious Radiation	Part 2.1053 27.53(m)	Pass
Frequency Stability	Part 2.1055 27.54	Pass
NOTE 1:For the verdict,the“N/A”denotes“not applicable”,the“N/T”denotes “nottested”.		

Remark:

1. The measurement uncertainty is not included in the test result.

3.3 Equipments Used during the Test

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Calibration Date	Calibration Due Date
1	L.I.S.N.	R&S	ENV216	HKE-002	2024/02/20	2025/02/19
2	L.I.S.N.	R&S	ENV216	HKE-059	2024/02/20	2025/02/19
3	EMI Test Receiver	R&S	ESR	HKE-005	2024/02/20	2025/02/19
4	Spectrum analyzer	Agilent	N9020A	HKE-117	2024/02/20	2025/02/19
5	Spectrum analyzer	R&S	FSV3044	HKE-126	2024/02/20	2025/02/19
6	Preamplifier	EMCI	EMC051845S	HKE-006	2024/02/20	2025/02/19
7	Preamplifier	Schwarzbeck	BBV 9743	HKE-016	2024/02/20	2025/02/19
8	Preamplifier	A.H. Systems	SAS-574	HKE-182	2024/02/20	2025/02/19
9	6dB Attenuator	Pasternack	6db	HKE-184	2024/02/20	2025/02/19
10	EMI Test Receiver	Rohde & Schwarz	ESR-7	HKE-010	2024/02/20	2025/02/19
11	Broadband Antenna	Schwarzbeck	VULB9168	HKE-167	2024/02/21	2026/02/20
12	Loop Antenna	COM-POWER	AL-130R	HKE-014	2024/02/21	2026/02/20
13	Horn Antenna	Schwarzbeck	9120D	HKE-013	2024/02/21	2026/02/20
14	EMI Test Software	Tonscend	JS32-CE 2.5.0.6	HKE-081	/	/
15	EMI Test Software	Tonscend	JS32-RE 5.0.0	HKE-082	/	/
16	RF Automatic control unit	Tonscend	JS0806-1	HKE-096	2024/02/20	2025/02/19
17	High pass filter unit	Tonscend	JS0806-F	HKE-055	2024/02/20	2025/02/19
18	Wireless Communication Test Set	R&S	CMU200	HKE-026	2024/02/20	2025/02/19
19	Wireless Communication Test Set	R&S	CMW500	HKE-027	2024/02/20	2025/02/19
20	High-low temperature chamber	Guangke	HT-80L	HKE-118	2024/06/10	2025/06/09
21	Temperature and humidity meter	Boyang	HTC-1	HKE-075	2024/06/10	2025/06/09
22	RF Test Software	Tonscend	JS1120 Version 3.5.39	HKE-183	/	/
23	RSE Test Software	Tonscend	JS36-RSE 5.0.0	HKE-184	/	/

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Item	Test Equipment	Manufacturer	Model No.	Serial No.	Calibration Date	Calibration Due Date
1	L.I.S.N.	R&S	ENV216	HKE-002	2025/02/19	2026/02/18
2	L.I.S.N.	R&S	ENV216	HKE-059	2025/02/19	2026/02/18
3	EMI Test Receiver	R&S	ESR	HKE-005	2025/02/19	2026/02/18
4	Spectrum analyzer	Agilent	N9020A	HKE-117	2025/02/19	2026/02/18
5	Spectrum analyzer	R&S	FSV3044	HKE-126	2025/02/19	2026/02/18
6	Preamplifier	EMCI	EMC051845S	HKE-006	2025/02/19	2026/02/18
7	Preamplifier	Schwarzbeck	BBV 9743	HKE-016	2025/02/19	2026/02/18
8	Preamplifier	A.H. Systems	SAS-574	HKE-182	2025/02/19	2026/02/18
9	6dB Attenuator	Pasternack	6db	HKE-184	2025/02/19	2026/02/18
10	EMI Test Receiver	Rohde & Schwarz	ESR-7	HKE-010	2024/02/20	2025/02/19
11	Broadband Antenna	Schwarzbeck	VULB9168	HKE-167	2024/02/21	2026/02/20
12	Loop Antenna	COM-POWER	AL-130R	HKE-014	2024/02/21	2026/02/20
13	Horn Antenna	Schwarzbeck	9120D	HKE-013	2024/02/21	2026/02/20
14	EMI Test Software	Tonscend	JS32-CE 2.5.0.6	HKE-081	/	/
15	EMI Test Software	Tonscend	JS32-RE 5.0.0	HKE-082	/	/
16	RF Automatic control unit	Tonscend	JS0806-1	HKE-096	2025/02/19	2026/02/18
17	High pass filter unit	Tonscend	JS0806-F	HKE-055	2025/02/19	2026/02/18
18	Wireless Communication Test Set	R&S	CMU200	HKE-026	2025/02/19	2026/02/18
19	Wireless Communication Test Set	R&S	CMW500	HKE-027	2025/02/19	2026/02/18
20	High-low temperature chamber	Guangke	HT-80L	HKE-118	2024/06/10	2025/06/09
21	Temperature and humidity meter	Boyang	HTC-1	HKE-075	2024/06/10	2025/06/09
22	RF Test Software	Tonscend	JS1120 Version 3.5.39	HKE-183	/	/
23	RSE Test Software	Tonscend	JS36-RSE 5.0.0	HKE-184	/	/

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4 Test Conditions and Results

4.1 Output Power

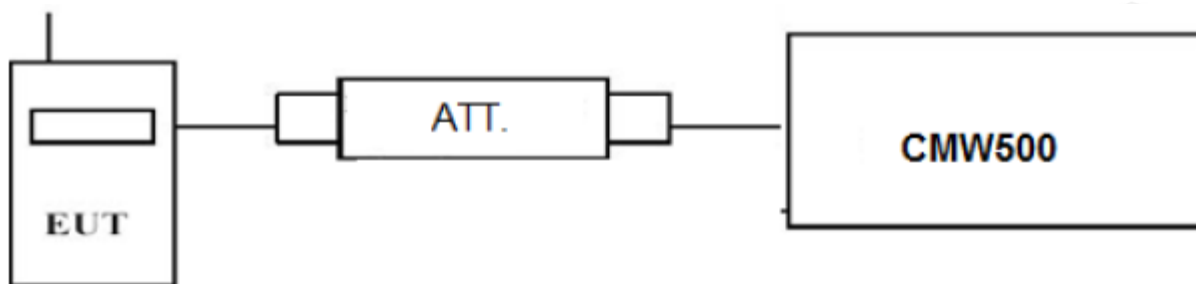
4.1.1 Conducted Output Power

TEST APPLICABLE

Part 27.50(h)(2) , during the process of testing, the EUT was controlled via R&S Digital Radio Communication tester (CMW500) to ensure max power transmission and proper modulation. This result contains output power measurements for the EUT. In all cases, output power is within the specified limits.

TEST CONFIGURATION

Conducted Power Measurement:



TEST PROCEDURE

Conducted Power Measurement:

- Place the EUT on a bench and set it in transmitting mode.
- Connect a low loss RF cable from the antenna port to a CMW500 by an Att.
- EUT Communicate with CMW500 then selects a channel for testing.
- Add a correction factor to the display CMW500, and then test.

TEST RESULTS

Remark:

1. We measured all RB Configuration refer 3GPP TS136 521 for each Channel Bandwidth of LTE Band 7;

LTE Band 7				
TX Channel Bandwidth	Frequency (MHz)	RB Size/Offset	Burst Average Power [dBm]	
			QPSK	16QAM
5 MHz	2502.5	1 RB low	20.81	19.76
		1 RB mid	20.90	19.86
		1 RB high	20.75	19.59
		50% RB low	19.75	18.80
		50% RB mid	19.87	18.60
		50% RB high	19.89	18.73
		100% RB	19.87	18.91
	2535	1 RB low	20.62	19.49
		1 RB mid	20.75	19.60
		1 RB high	20.58	19.47
		50% RB low	19.67	18.56
		50% RB mid	19.65	18.62
		50% RB high	19.59	18.46
		100% RB	19.58	18.56
	2567.5	1 RB low	20.28	19.33
		1 RB mid	20.51	19.43
		1 RB high	20.42	19.30
		50% RB low	19.39	18.37
		50% RB mid	19.43	18.36
		50% RB high	19.39	18.35
		100% RB	19.40	18.41
10 MHz	2505	1 RB low	20.80	19.81
		1 RB mid	20.88	19.92
		1 RB high	20.80	19.84
		50% RB low	19.89	18.84
		50% RB mid	19.88	18.86
		50% RB high	19.90	18.88
		100% RB	19.85	18.86
	2535	1 RB low	20.66	19.61
		1 RB mid	20.73	19.63
		1 RB high	20.55	19.50
		50% RB low	19.66	18.65
		50% RB mid	19.67	18.61
		50% RB high	19.58	18.55
		100% RB	19.62	18.58
	2565	1 RB low	20.38	19.34
		1 RB mid	20.41	19.46
		1 RB high	20.38	19.33
		50% RB low	19.34	18.34
		50% RB mid	19.36	18.35
		50% RB high	19.44	18.39
		100% RB	19.35	18.37

15 MHz	2507.5	1 RB low	20.74	19.77
		1 RB mid	20.80	19.76
		1 RB high	20.72	19.70
		50% RB low	20.91	19.93
		50% RB mid	20.94	19.94
		50% RB high	19.94	19.91
		100% RB	19.91	18.82
	2535	1 RB low	20.67	19.61
		1 RB mid	20.59	19.54
		1 RB high	20.47	19.45
		50% RB low	19.75	19.72
		50% RB mid	20.70	19.72
		50% RB high	20.70	19.70
		100% RB	19.73	18.59
	2562.5	1 RB low	20.36	19.35
		1 RB mid	20.32	19.29
		1 RB high	20.27	19.23
		50% RB low	20.35	19.38
		50% RB mid	20.39	19.42
		50% RB high	19.40	19.37
		100% RB	19.42	18.31
20 MHz	2510	1 RB low	20.64	19.55
		1 RB mid	20.96	19.79
		1 RB high	20.46	19.26
		50% RB low	19.82	18.76
		50% RB mid	19.81	18.78
		50% RB high	19.86	18.79
		100% RB	19.65	18.64
	2535	1 RB low	20.59	19.35
		1 RB mid	20.74	19.61
		1 RB high	20.34	19.02
		50% RB low	19.71	18.63
		50% RB mid	19.72	18.61
		50% RB high	19.43	18.46
		100% RB	19.57	18.54
	2560	1 RB low	20.22	18.89
		1 RB mid	20.11	18.81
		1 RB high	19.72	18.58
		50% RB low	18.84	17.78
		50% RB mid	18.85	17.82
		50% RB high	18.89	17.89
		100% RB	18.86	17.86

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4.1.2. Radiated Output Power

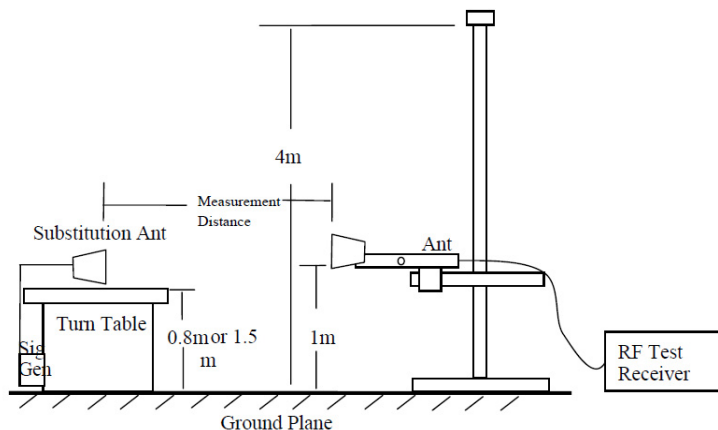
LIMIT

This is the test for the maximum radiated power from the EUT.

TEST CONFIGURATION

Radiated Power Measurement:

remark : 0.8m for below 1GHz, 1.5m for above 1GHz



TEST PROCEDURE

The EUT was setup according to EIA/TIA 603D

- The EUT shall be placed at the specified height on a support, and in the position closest to normal use as declared by provider.
- The test antenna shall be oriented initially for vertical polarization and shall be chosen to correspond to the frequency of the transmitter.
- The output of the test antenna shall be connected to the measuring receiver.
- The transmitter shall be switched on and the measuring receiver shall be tuned to the frequency of the transmitter under test.
- The test antenna shall be raised and lowered through the specified range of height until a maximum signal level is detected by the measuring receiver.
- The transmitter shall then be rotated through 360° in the horizontal plane, until the maximum signal level is detected by the measuring receiver.
- The test antenna shall be raised and lowered again through the specified range of height until a maximum signal level is detected by the measuring receiver.
- The maximum signal level detected by the measuring receiver shall be noted.
- The transmitter shall be replaced by a substitution antenna.
- The substitution antenna shall be orientated for vertical polarization and the length of the substitution antenna shall be adjusted to correspond to the frequency of the transmitter.
- The substitution antenna shall be connected to a calibrated signal generator.
- If necessary, the input attenuator setting of the measuring receiver shall be adjusted in order to increase the sensitivity of the measuring receiver.
- The test antenna shall be raised and lowered through the specified range of height to ensure that the maximum signal is received.
- The input signal to the substitution antenna shall be adjusted to the level that produces a level detected by the measuring receiver, that is equal to the level noted while the transmitter radiated power was measured, corrected for the change of input attenuator setting of the measuring receiver.
- The measurement shall be repeated with the test antenna and the substitution antenna orientated for horizontal polarization.
- The measure of the effective radiated power is the larger of the two levels recorded at the input to the substitution antenna, corrected for gain of the substitution antenna if necessary.
- Test site anechoic chamber refer to ANSI C63.4.

TEST RESULTS

Radiated Measurement:

Remark:

1. We measured all RB Configuration refer 3GPP TS136 521 for each Channel Bandwidth of LTE Band 7; recorded worst case for each Channel Bandwidth of LTE Band 7.
2. $EIRP = P_s(dBm) - P_{cl}(dB) + G_a(dBi)$
3. We measured both Horizontal and Vertical direction, recorded worst case direction.

LTE Band 7 Channel Bandwidth 5MHz_QPSK_1RB#0

Frequency (MHz)	P_s (dBm)	P_{cl} (dB)	G_a Antenna Gain(dB)	Burst Average EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
2502.5	7.70	3.41	15.12	19.41	33.01	13.60	V
2535	7.25	3.49	15.12	18.88	33.01	14.13	V
2567.5	7.04	3.55	15.12	18.61	33.01	14.40	V

LTE Band 7 Channel Bandwidth 10MHz_QPSK_1RB#0

Frequency (MHz)	P_s (dBm)	P_{cl} (dB)	G_a Antenna Gain(dB)	Burst Average EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
2505	8.37	3.41	15.12	20.08	33.01	12.93	V
2535	7.44	3.49	15.12	19.07	33.01	13.94	V
2565	6.26	3.55	15.12	17.83	33.01	15.18	V

LTE Band 7 Channel Bandwidth 15MHz_QPSK_1RB#0

Frequency (MHz)	P_s (dBm)	P_{cl} (dB)	G_a Antenna Gain(dB)	Burst Average EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
2507.5	7.53	3.41	15.12	19.24	33.01	13.77	V
2535	7.57	3.49	15.12	19.20	33.01	13.81	V
2562.5	6.94	3.55	15.12	18.51	33.01	14.50	V

LTE Band 7 Channel Bandwidth 20MHz_QPSK_1RB#0

Frequency (MHz)	P_s (dBm)	P_{cl} (dB)	G_a Antenna Gain(dB)	Burst Average EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
2510	7.37	3.41	15.12	19.08	33.01	13.93	V
2535	7.09	3.49	15.12	18.72	33.01	14.29	V
2560	8.67	3.55	15.12	20.24	33.01	12.77	V

LTE Band 7 Channel Bandwidth 5MHz 16QAM 1RB#0

Frequency (MHz)	P _s (dBm)	P _{cl} (dB)	G _a Antenna Gain(dB)	Burst Average EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
2502.5	6.94	3.41	15.12	18.65	33.01	14.36	V
2535	8.10	3.49	15.12	19.73	33.01	13.28	V
2567.5	8.61	3.55	15.12	20.18	33.01	12.83	V

LTE Band 7 Channel Bandwidth 10MHz 16QAM 1RB#0

Frequency (MHz)	P _s (dBm)	P _{cl} (dB)	G _a Antenna Gain(dB)	Burst Average EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
2505	6.96	3.41	15.12	18.67	33.01	14.34	V
2535	7.01	3.49	15.12	18.64	33.01	14.37	V
2565	7.22	3.55	15.12	18.79	33.01	14.22	V

LTE Band 7 Channel Bandwidth 15MHz 16QAM 1RB#0

Frequency (MHz)	P _s (dBm)	P _{cl} (dB)	G _a Antenna Gain(dB)	Burst Average EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
2507.5	6.56	3.41	15.12	18.27	33.01	14.74	V
2535	8.31	3.49	15.12	19.94	33.01	13.07	V
2562.5	7.25	3.55	15.12	18.82	33.01	14.19	V

LTE Band 7 Channel Bandwidth 20MHz 16QAM 1RB#0

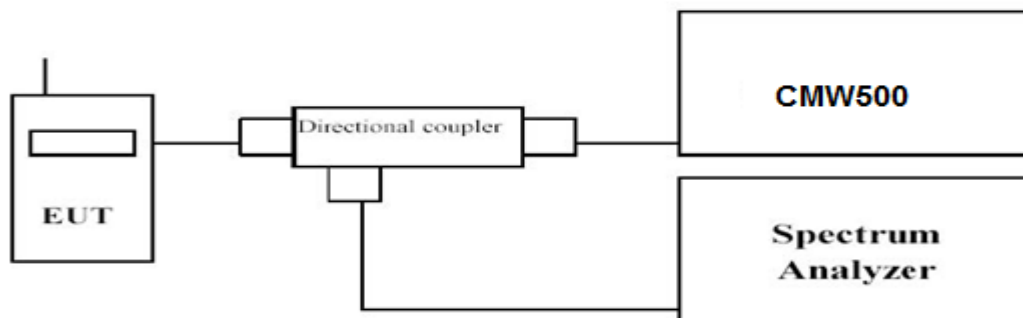
Frequency (MHz)	P _s (dBm)	P _{cl} (dB)	G _a Antenna Gain(dB)	Burst Average EIRP (dBm)	Limit (dBm)	Margin (dB)	Polarization
2510	4.82	3.41	15.12	16.53	33.01	16.48	V
2535	7.53	3.49	15.12	19.16	33.01	13.85	V
2560	9.22	3.55	15.12	20.79	33.01	12.22	V

4.2 Peak-to-Average Ratio (PAR)

LIMIT

The Peak-to-Average Ratio (PAR) of the transmission may not exceed 13 dB.

TEST CONFIGURATION



TEST PROCEDURE

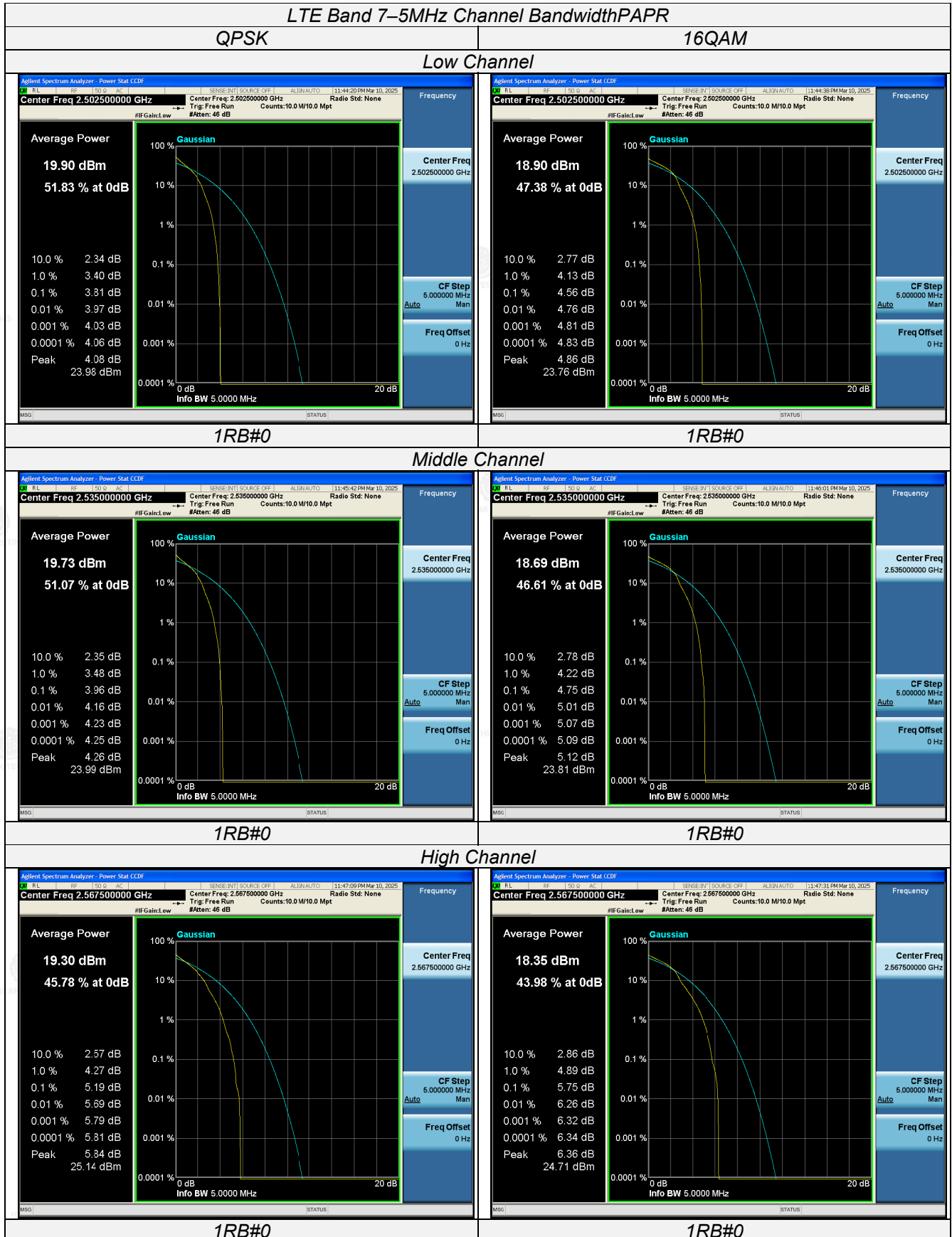
1. Refer to instrument's analyzer instruction manual for details on how to use the power statistics/CCDF function;
2. Set resolution/measurement bandwidth $\geq$ signal's occupied bandwidth;
3. Set the number of counts to a value that stabilizes the measured CCDF curve;
4. Set the measurement interval as follows:
 - 1). for continuous transmissions, set to 1 ms,
 - 2). for burst transmissions, employ an external trigger that is synchronized with the EUT burst timing sequence, or use the internal burst trigger with a trigger level that allows the burst to stabilize and set the measurement interval to a time that is less than or equal to the burst duration.
5. Record the maximum PAPR level associated with a probability of 0.1%.

TEST RESULTS

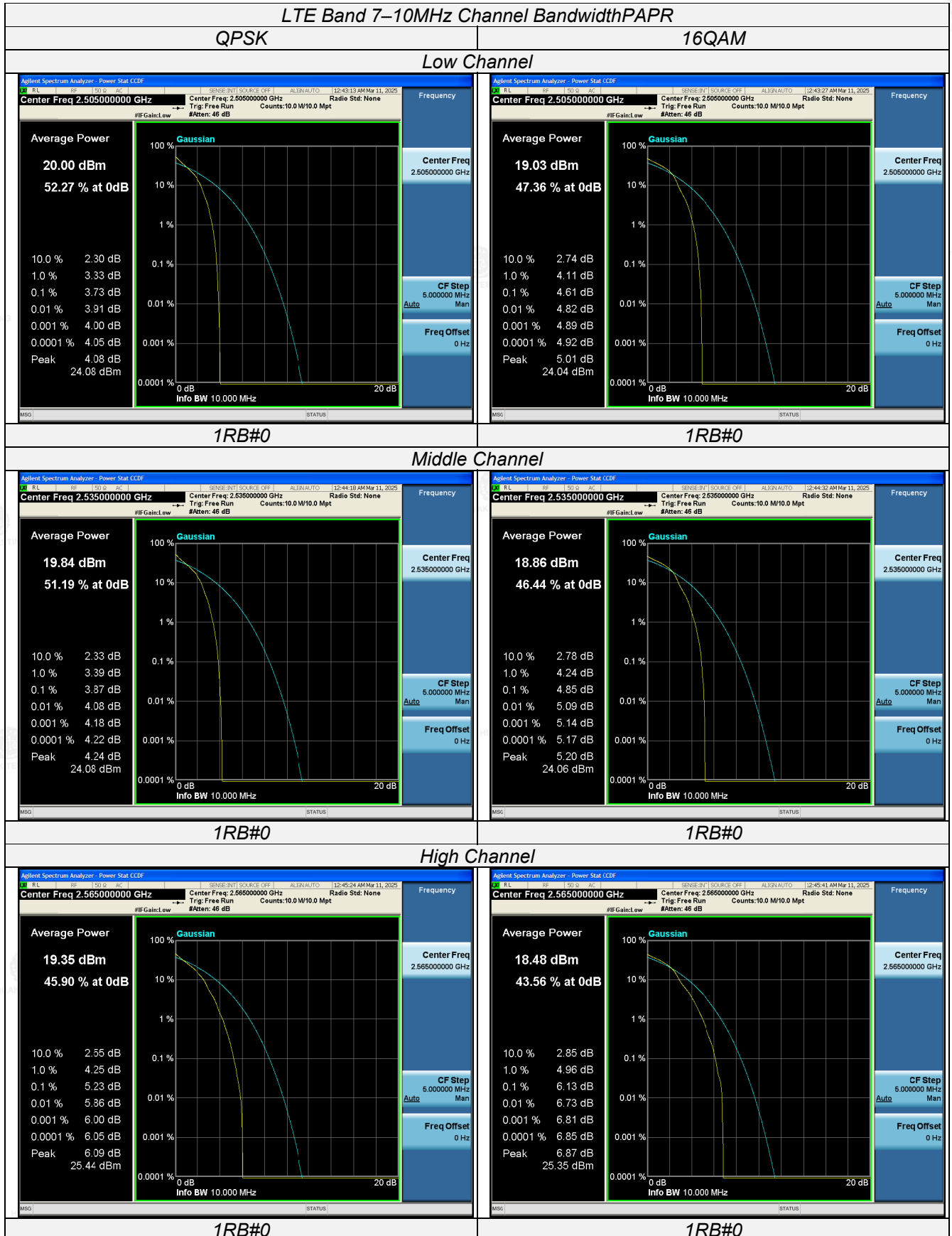
Remark:

1. We measured all RB Configuration refer 3GPP TS136 521 for each Channel Bandwidth of LTE Band 7; recorded worst case for each Channel Bandwidth of LTE Band 7.

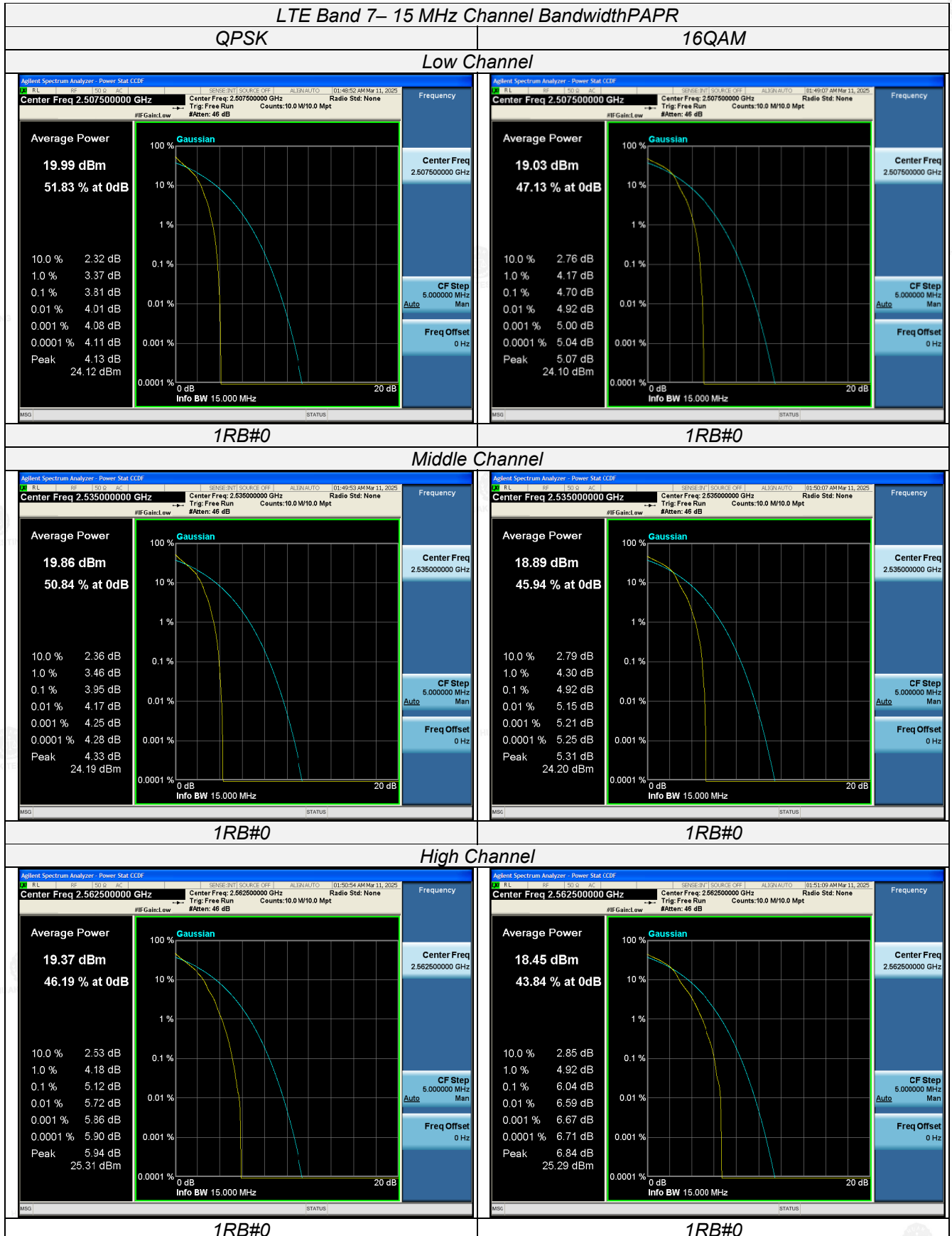
LTE Band 7				
TX Channel Bandwidth	Frequency (MHz)	RB Size/Offset	PAPR(dB)	
			QPSK	16QAM
5 MHz	2502.5	1RB#0	3.81	4.56
	2535		3.96	4.75
	2567.5		5.19	5.75
10 MHz	2505	1RB#0	3.73	4.61
	2535		3.87	4.85
	2565		5.23	6.13
15 MHz	2507.5	1RB#0	3.81	4.70
	2535		3.95	4.92
	2562.5		5.12	6.04
20 MHz	2510	1RB#0	3.91	4.69
	2535		4.13	4.92
	2560		4.82	5.51



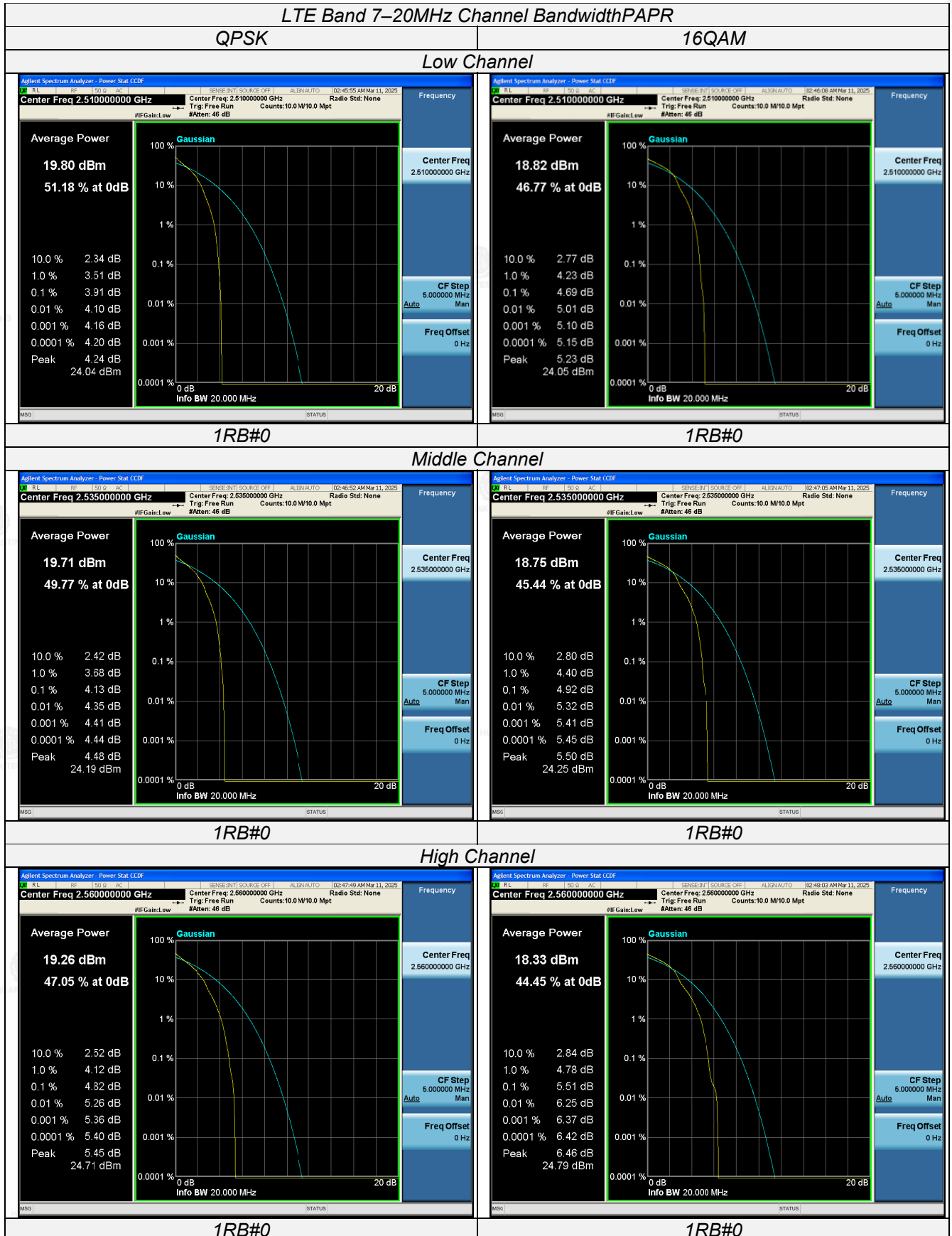
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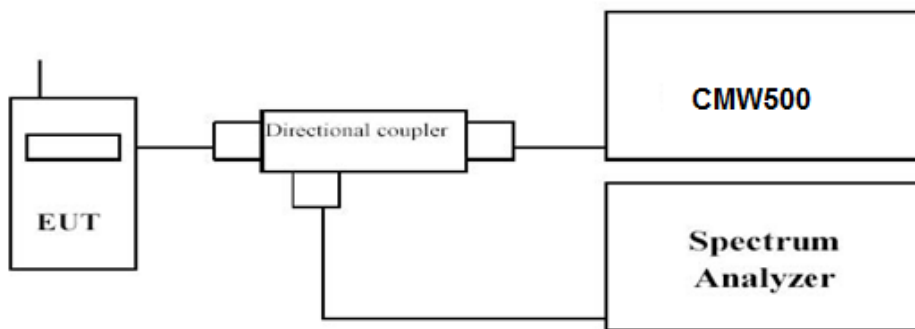
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4.3 Occupied Bandwidth and Emission Bandwidth

LIMIT

N/A

TEST CONFIGURATION



TEST PROCEDURE

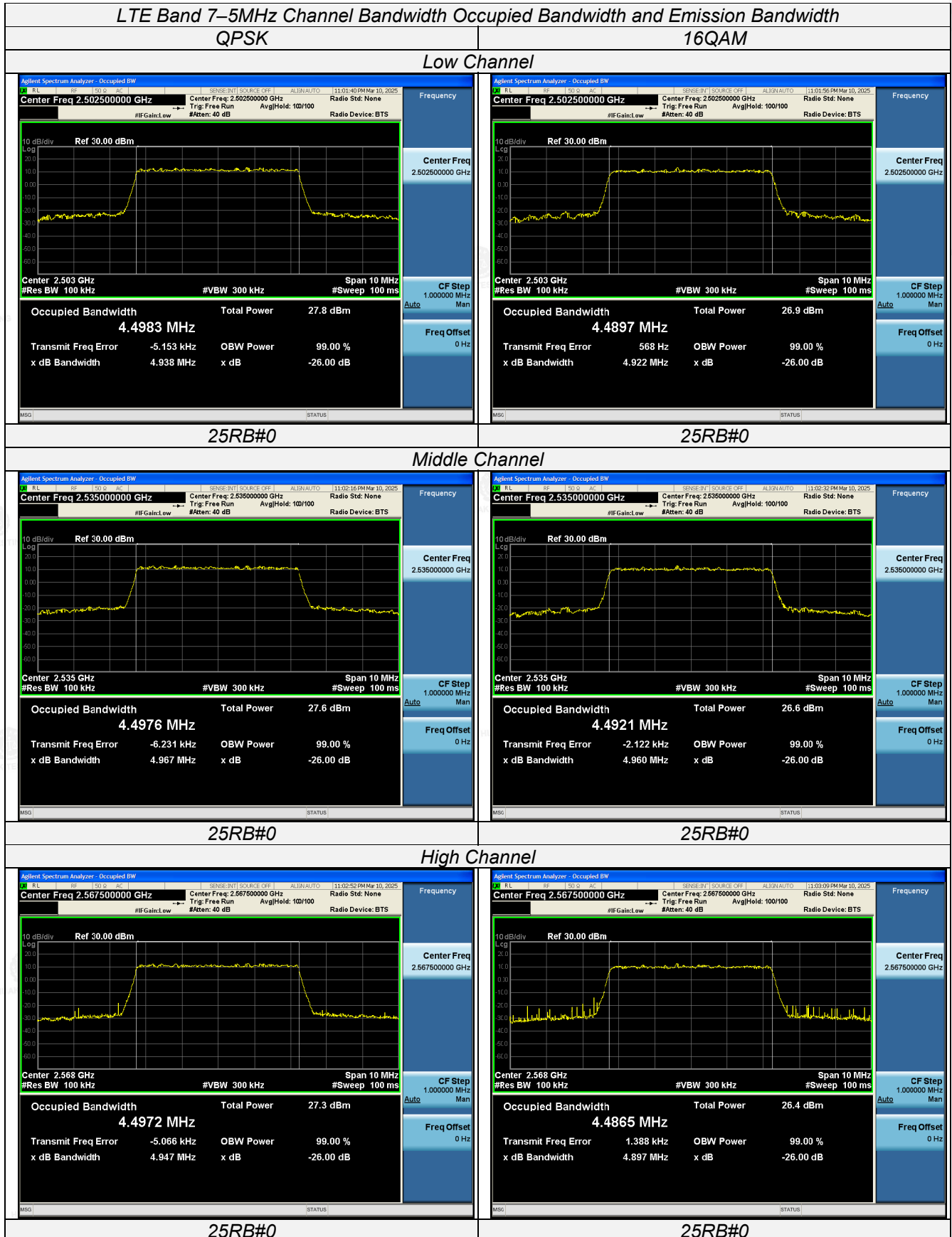
The transmitter output was connected to a calibrated coaxial cable and coupler, the other end of which was connected to a spectrum analyzer. The occupied bandwidth was measured with the spectrum analyzer at low, middle and high channel in each band. The -26dBc Emission bandwidth was also measured and recorded. Set RBW was set to about 1% of emission BW, VBW ≥ 3 times RBW. -26dBc display line was placed on the screen (or 99% bandwidth), the occupied bandwidth is the delta frequency between the two points where the display line intersects the signal trace.

TEST RESULTS

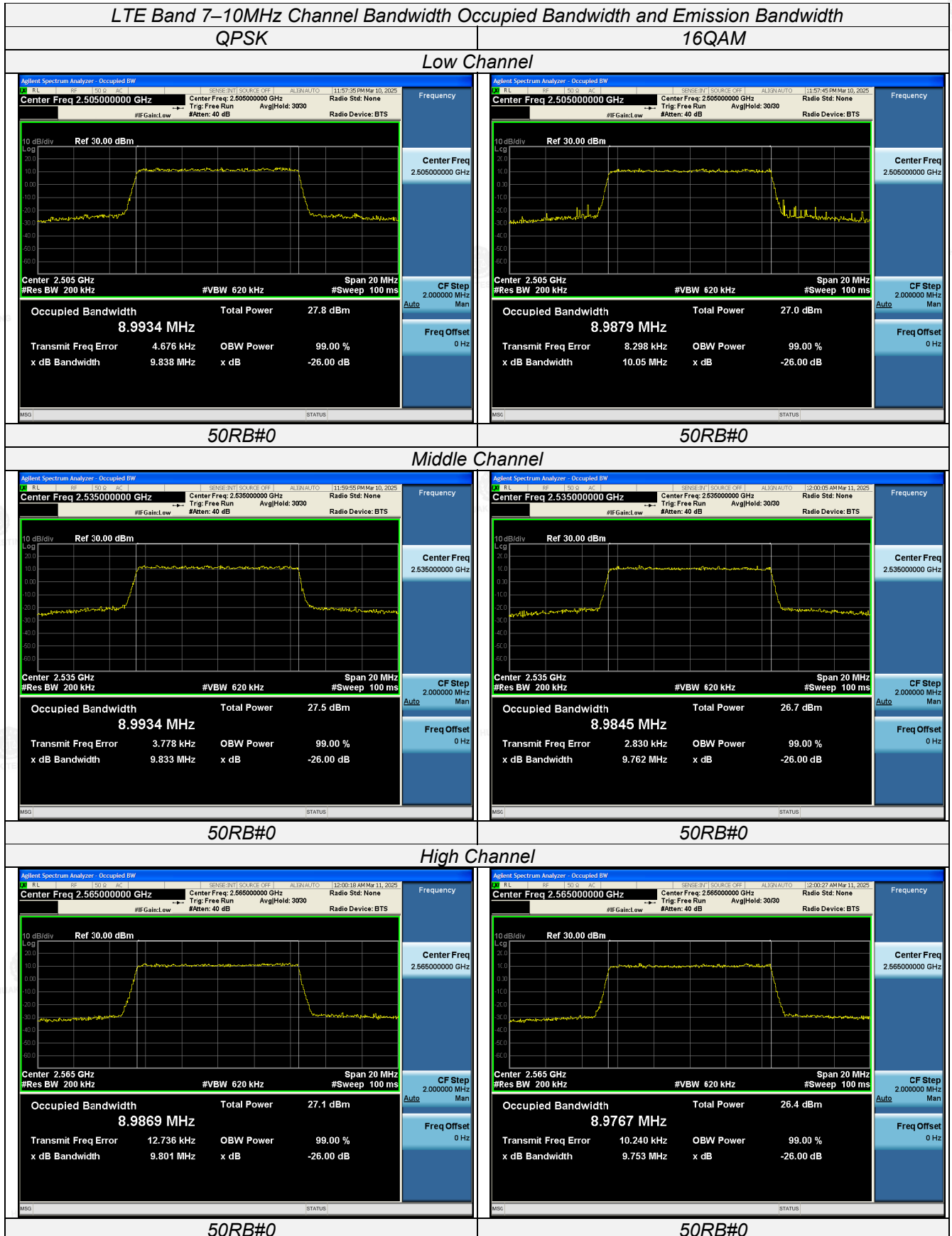
Remark:

1. We were tested all RB Configuration refer 3GPP TS136 521 for each Channel Bandwidth of LTE Band 7; recorded worst case for each Channel Bandwidth of LTE Band 7.

LTE Band 7						
TX Channel Bandwidth	RB Size/Offset	Frequency (MHz)	99% Occupied bandwidth (MHz)		-26dBc Emission bandwidth (MHz)	
			QPSK	16QAM	QPSK	16QAM
5 MHz	25RB#0	2502.5	4.4983	4.4897	4.938	4.922
		2535	4.4976	4.4921	4.967	4.960
		2567.5	4.4972	4.4865	4.947	4.897
10 MHz	50RB#0	2505	8.9934	8.9879	9.838	10.05
		2535	8.9934	8.9845	9.833	9.762
		2565	8.9869	8.9767	9.801	9.753
15 MHz	75RB#0	2507.5	13.476	13.492	14.73	14.66
		2535	13.503	13.497	14.77	14.59
		2562.5	13.471	13.462	14.63	14.66
20 MHz	100RB#0	2510	17.937	17.948	19.43	19.36
		2535	17.966	17.977	19.69	19.34
		2560	17.942	18.010	19.37	19.39



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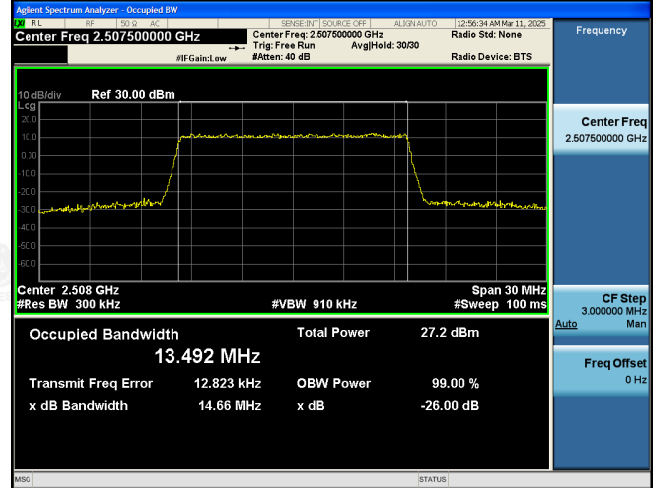
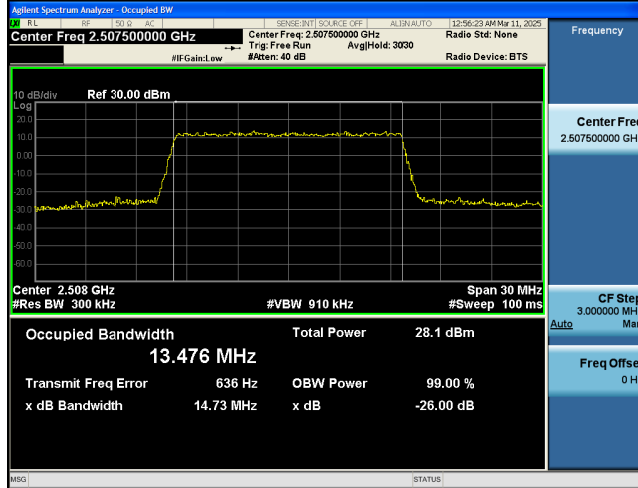
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LTE Band 7-15MHz Channel Bandwidth Occupied Bandwidth and Emission Bandwidth

QPSK

16QAM

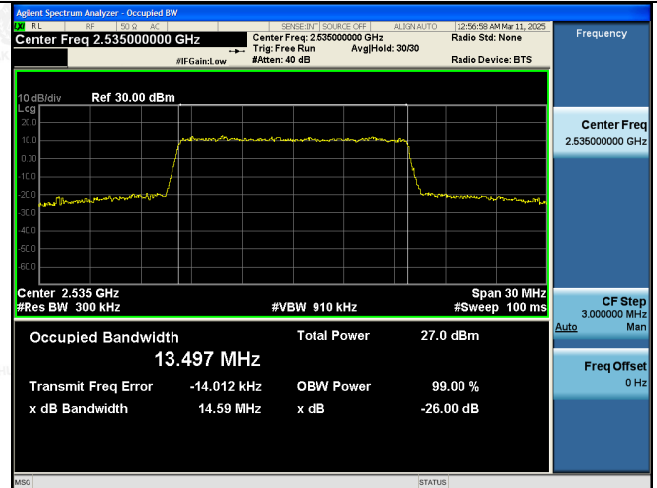
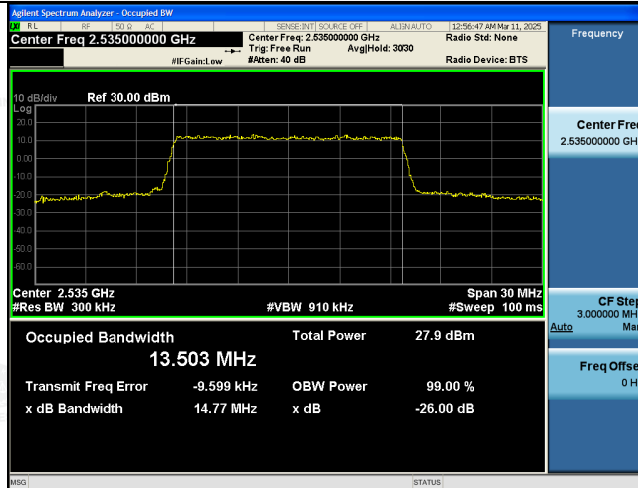
Low Channel



75RB#0

75RB#0

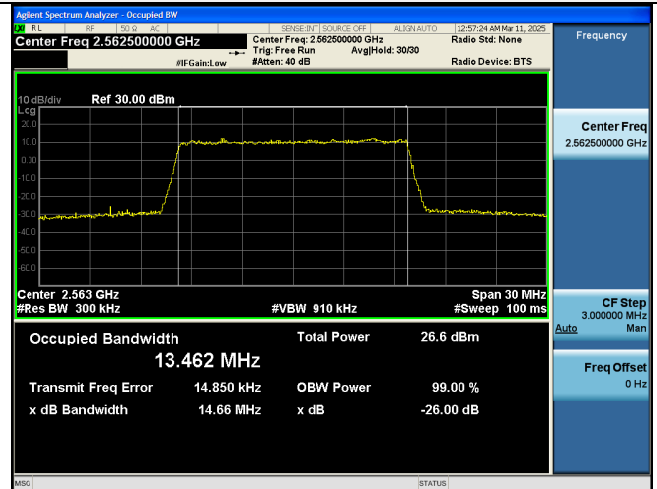
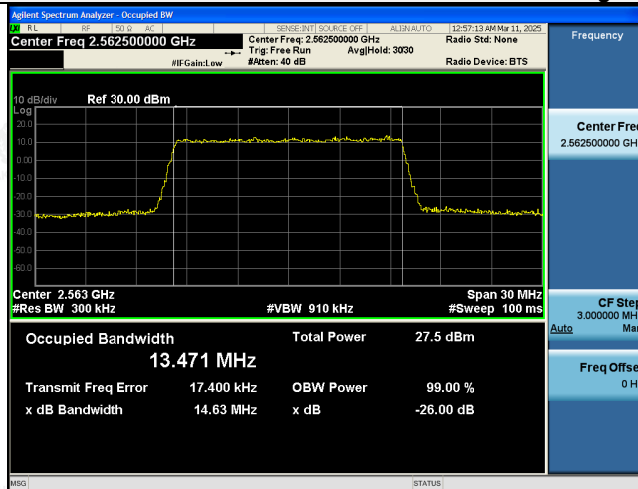
Middle Channel



75RB#0

75RB#0

High Channel

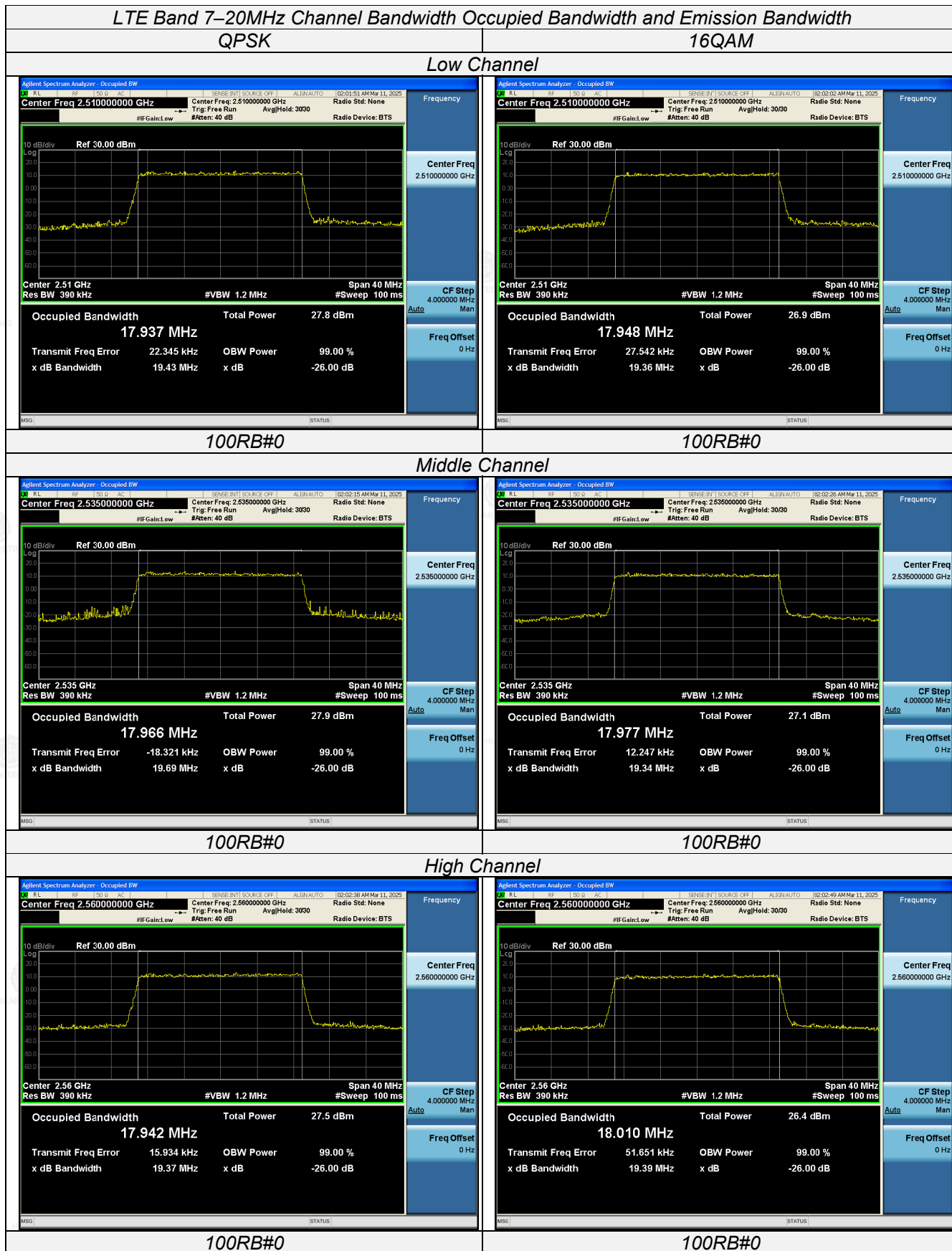


75RB#0

75RB#0

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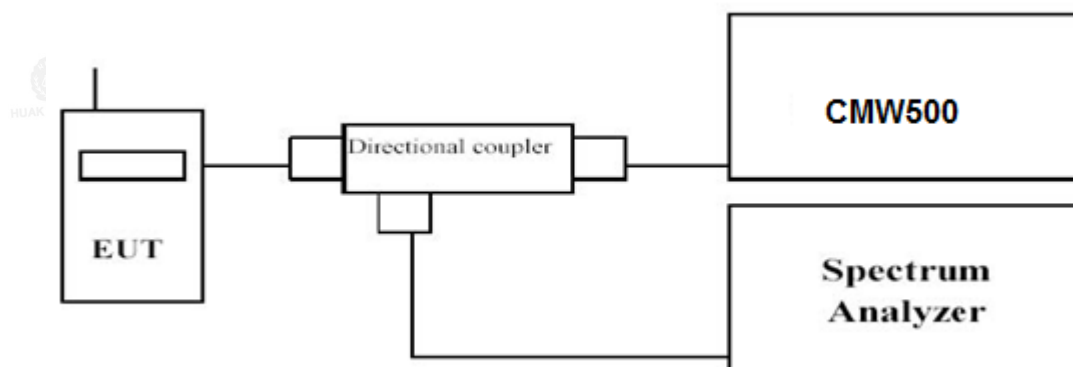
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4.4 Band Edge Compliance

LIMIT

the power of any emission outside of the authorized operating frequency ranges must be attenuated below the transmitting power (P) by a factor of at least $40 + 10 \log P$ dB (-10 dBm, 100 nW) on all frequencies between the channel edge and 5 MHz from the channel edge, $43 + 10 \log P$ dB (-13 dBm, 50 nW) on all frequencies between 5 MHz and X MHz from the channel edge, and $55 + 10 \log P$ dB (-25 dBm, 3 nW) on all frequencies more than 20 MHz from the channel edge, where XMHz is the greater of 6 MHz or the actual emission bandwidth (26 dB).

TEST CONFIGURATION



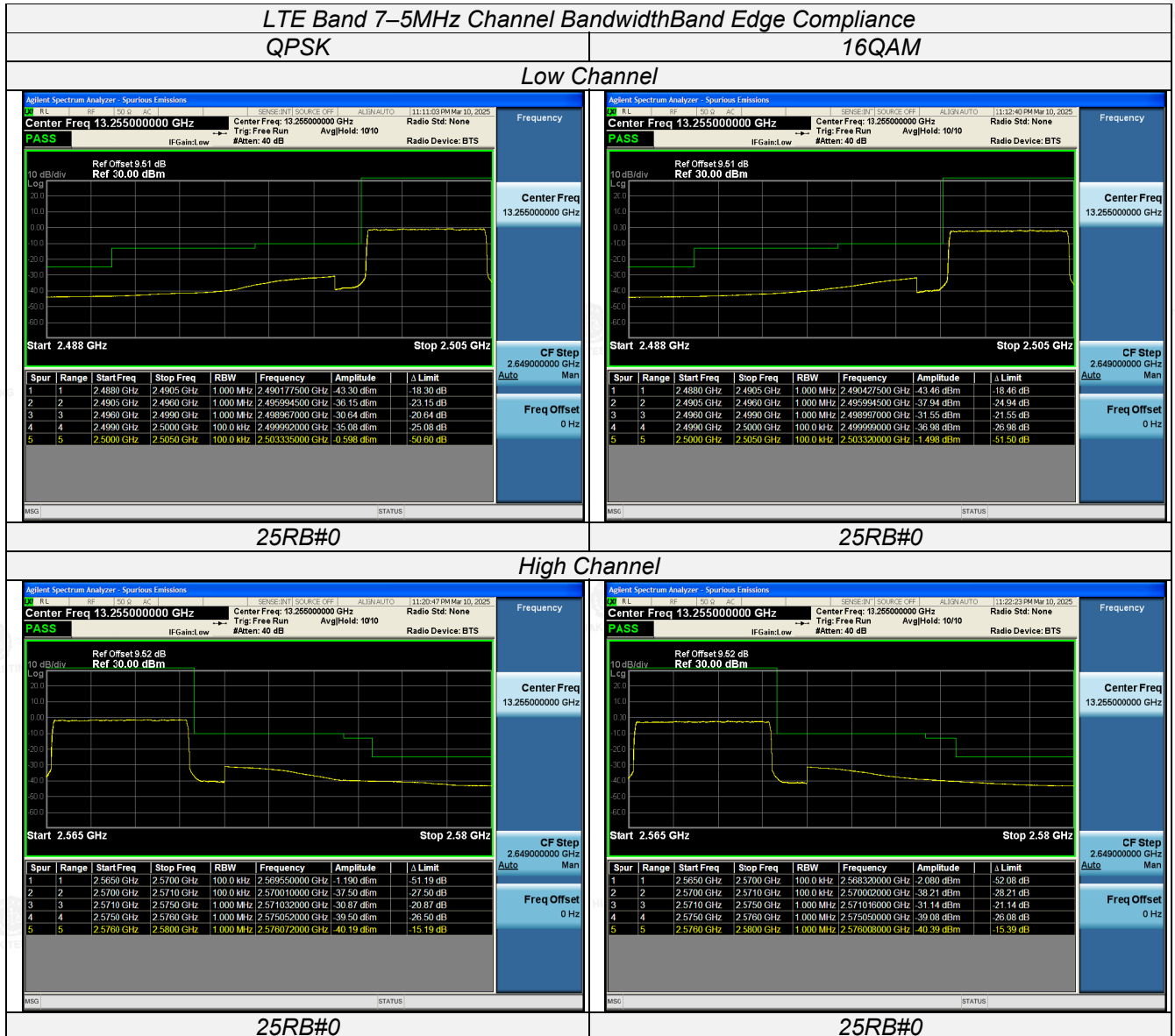
TEST PROCEDURE

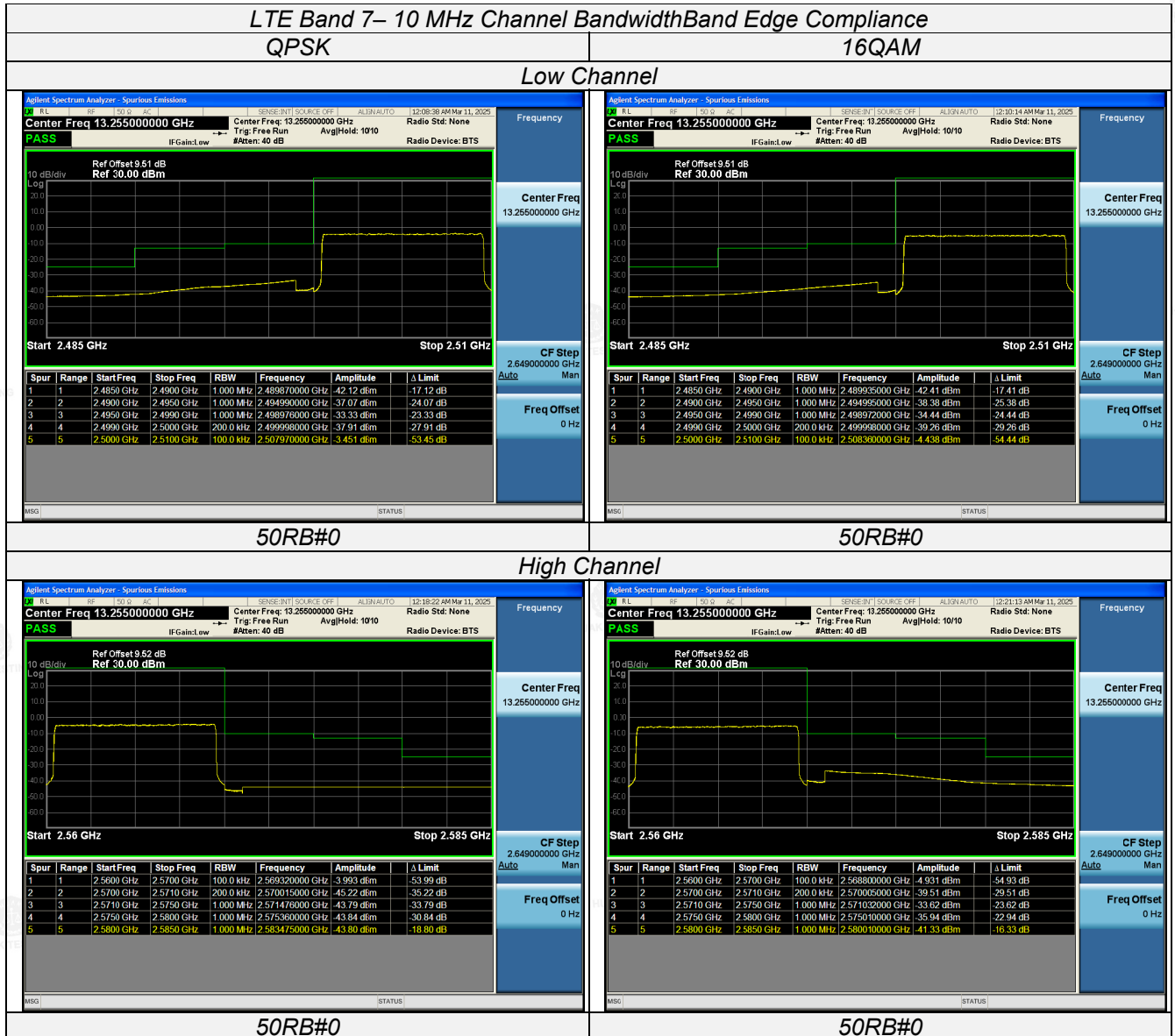
1. The transmitter output port was connected to base station.
2. The RF output of EUT was connected to the power meter by RF cable and attenuator, the path loss was compensated to the results for each measurement.
3. Set EUT at maximum power through base station.
4. Select lowest and highest channels for each band and different modulation.
5. Measure Band edge using RMS (Average) detector by spectrum
6. Set RBW = 100 kHz, VBW=300 kHz, Span=50MHz Peak Detector.

TEST RESULTS

Remark:

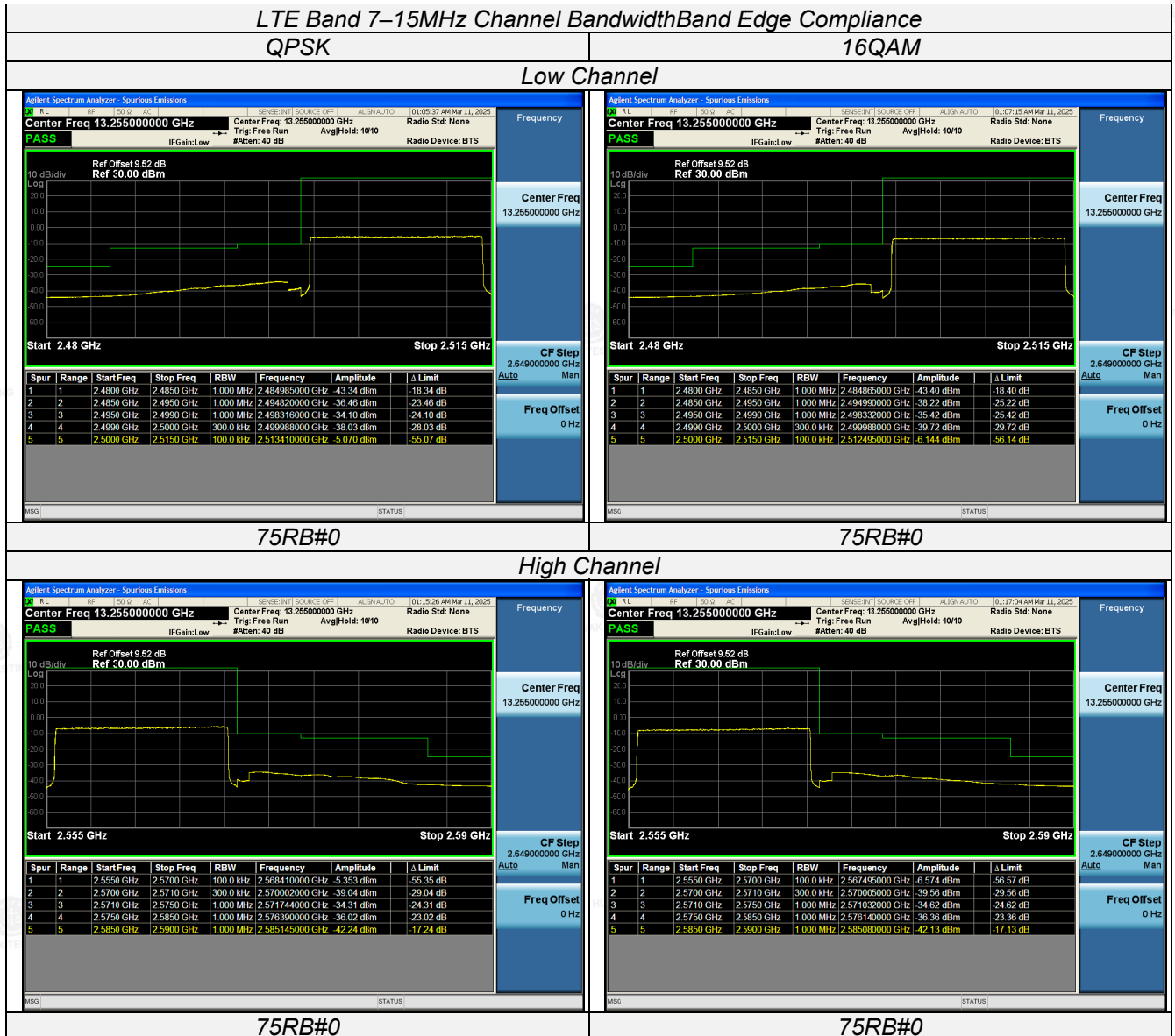
1. We were tested all RB Configuration refer 3GPP TS136 521 for each Channel Bandwidth of LTE Band 7; recorded worst case for each Channel Bandwidth of LTE Band 7.





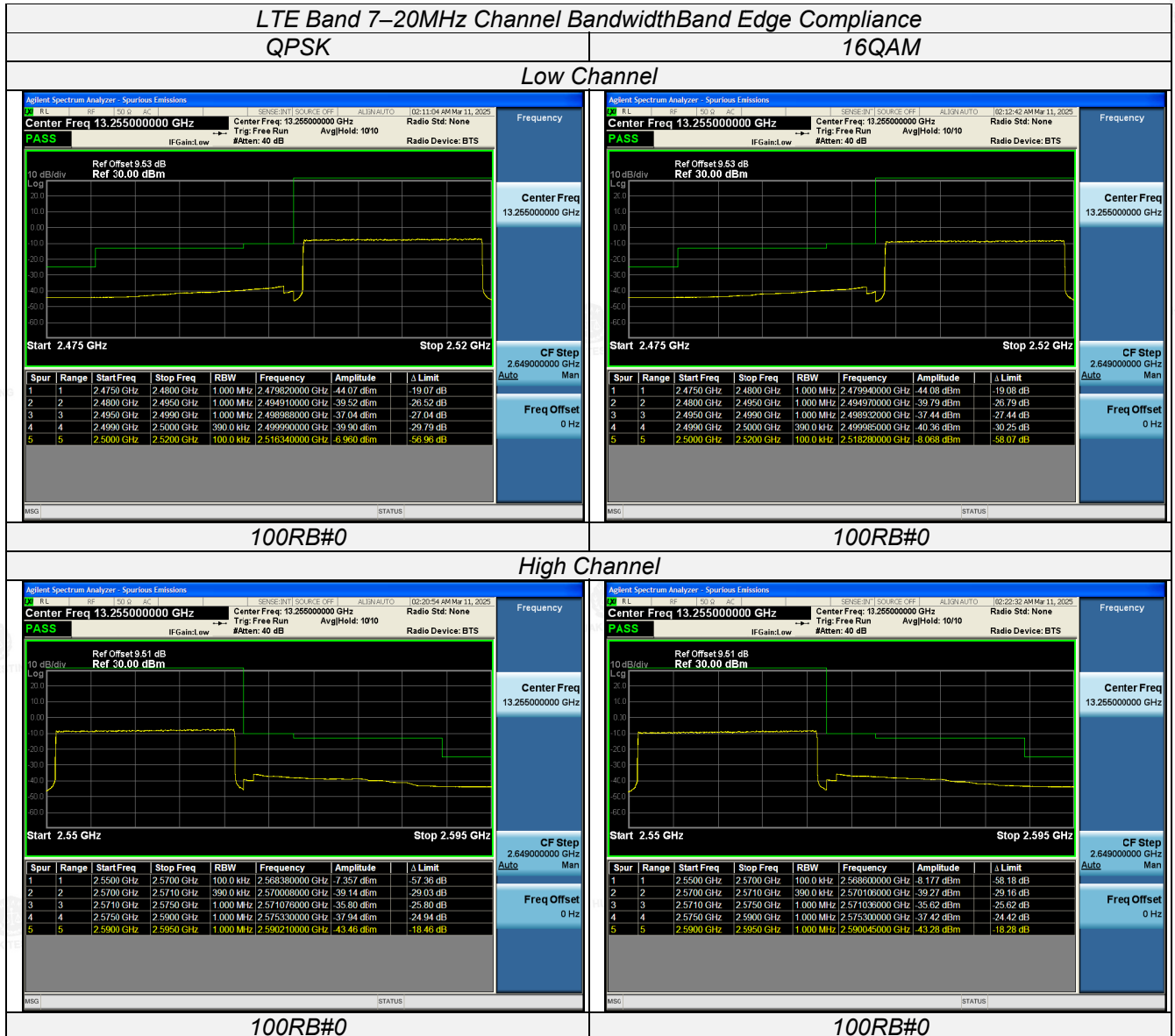
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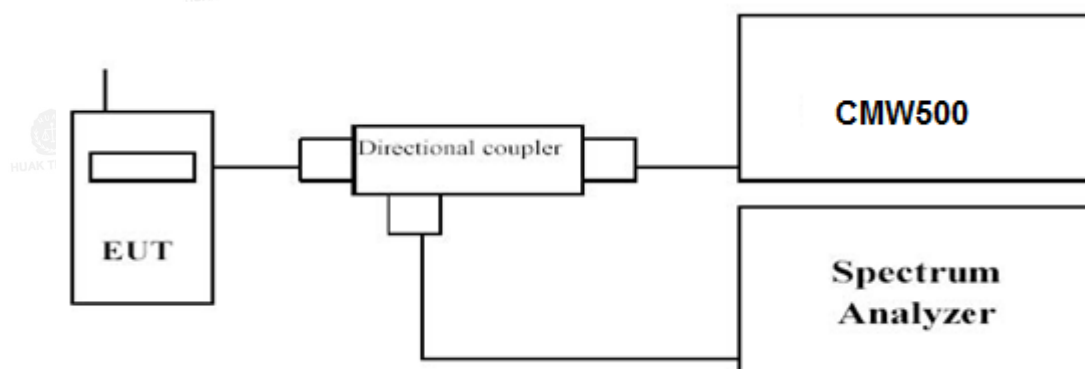
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4.5 Spurious Emission Antenna Port

LIMIT

The power of any emission outside of the authorized operating frequency ranges must be attenuated below the transmitting power (P) by a factor of at least $40 + 10 \log P$ dB (−10 dBm, 100 nW) on all frequencies between the channel edge and 5 MHz from the channel edge, $43 + 10 \log P$ dB (−13 dBm, 50 nW) on all frequencies between 5 MHz and X MHz from the channel edge, and $55 + 10 \log P$ dB (−25 dBm, 3 nW) on all frequencies more than 20 MHz from the channel edge, where X MHz is the greater of 6 MHz or the actual emission bandwidth (26 dB).

TEST CONFIGURATION



TEST PROCEDURE

The EUT was setup according to EIA/TIA 603D

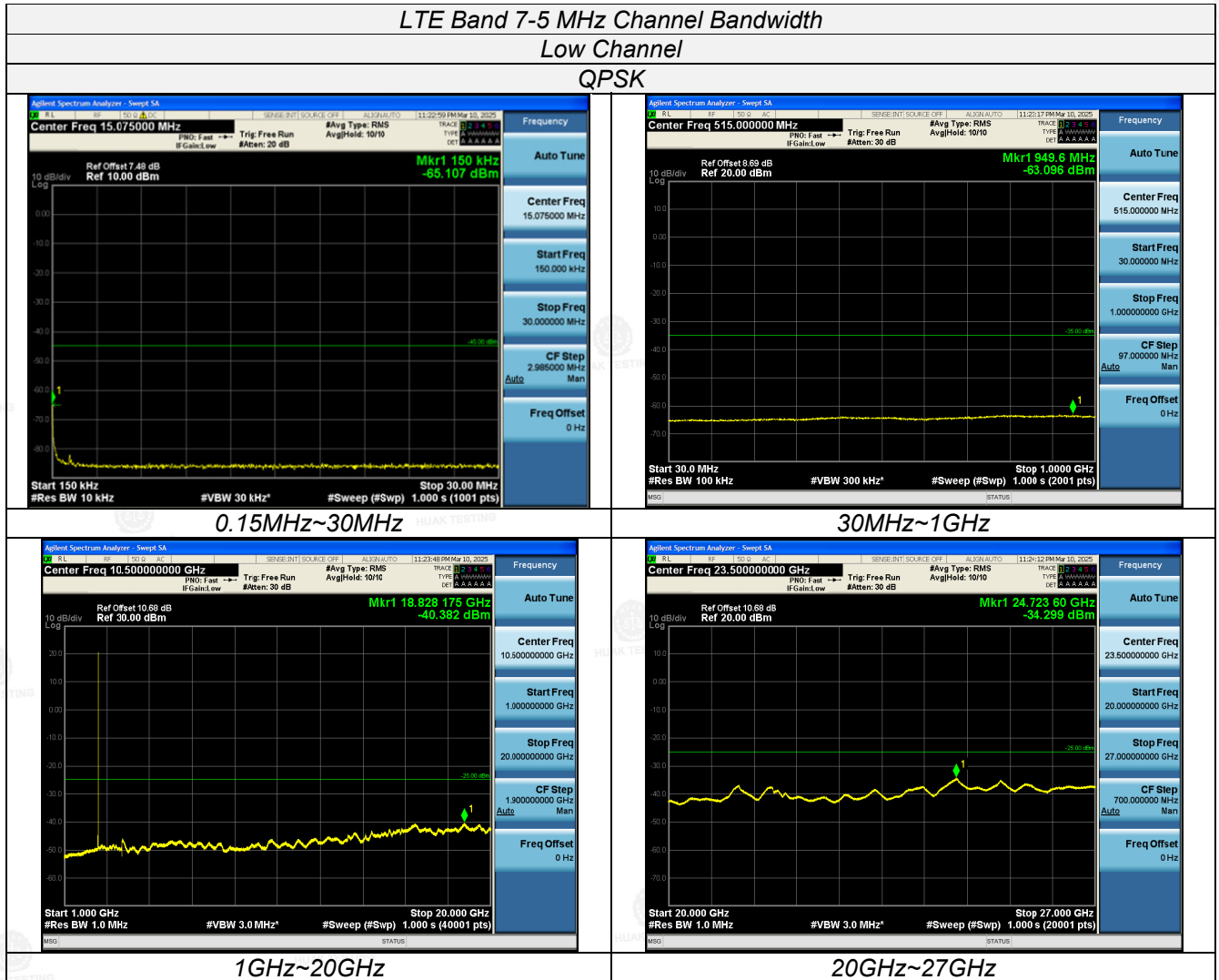
- Place the EUT on a bench and set it in transmitting mode.
- Connect a low loss RF cable from the antenna port to a spectrum analyzer and CMW500 by a Directional Couple.
- EUT Communicate with CMW500, then select a channel for testing.
- Add a correction factor to the display of spectrum, and then test.
- The resolution bandwidth of the spectrum analyzer was set sufficient scans were taken to show the out of band Emission if any up to 10th harmonic.
- Please refer to following tables for test antenna conducted emissions.

Working Frequency	Sub range (GHz)	RBW	VBW	Sweep time (s)
LTE Band 7	0.00015~0.03	10 KHz	30 KHz	Auto
	0.03~1	100 KHz	300 KHz	Auto
	1~20	1 MHz	3 MHz	Auto
	20~27	1 MHz	3 MHz	Auto

TEST RESULTS

Remark:

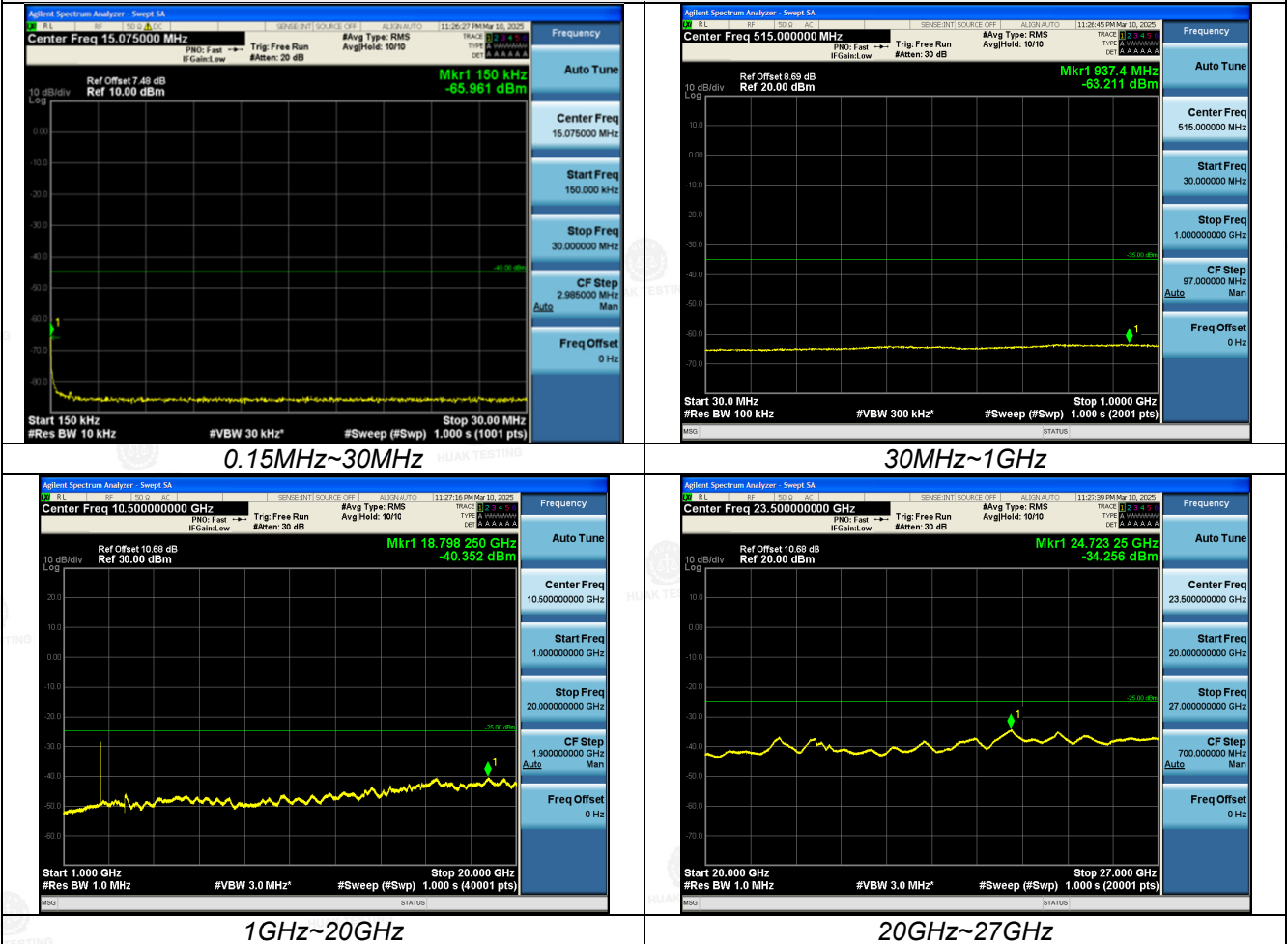
- We were tested all RB Configuration refer 3GPP TS136 521 for each Channel Bandwidth of LTE Band 7; recorded worst case at the QPSK Mode for each Channel Bandwidth of LTE Band 7



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LTE Band 7-5 MHz Channel Bandwidth
Middle Channel

QPSK

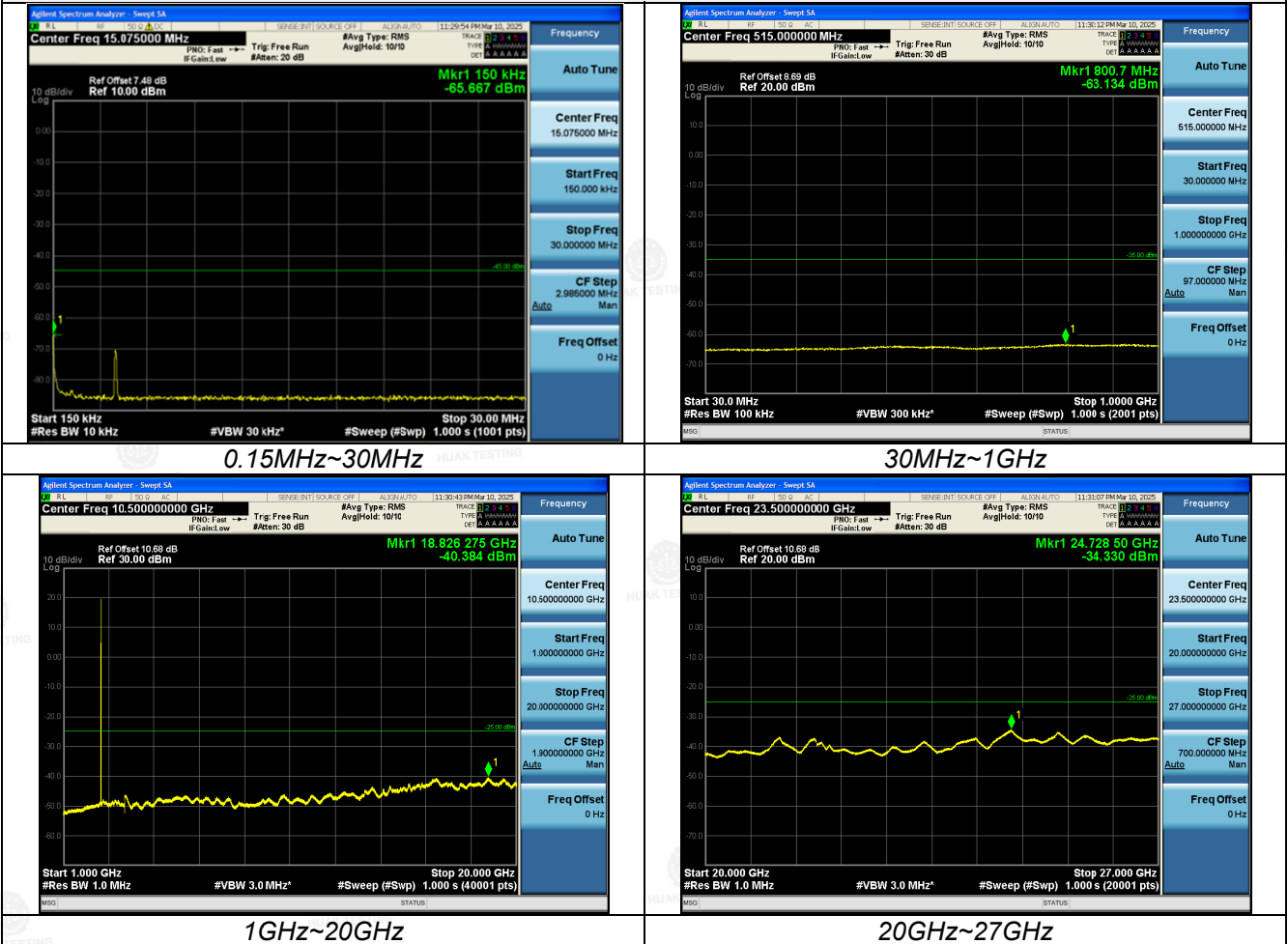


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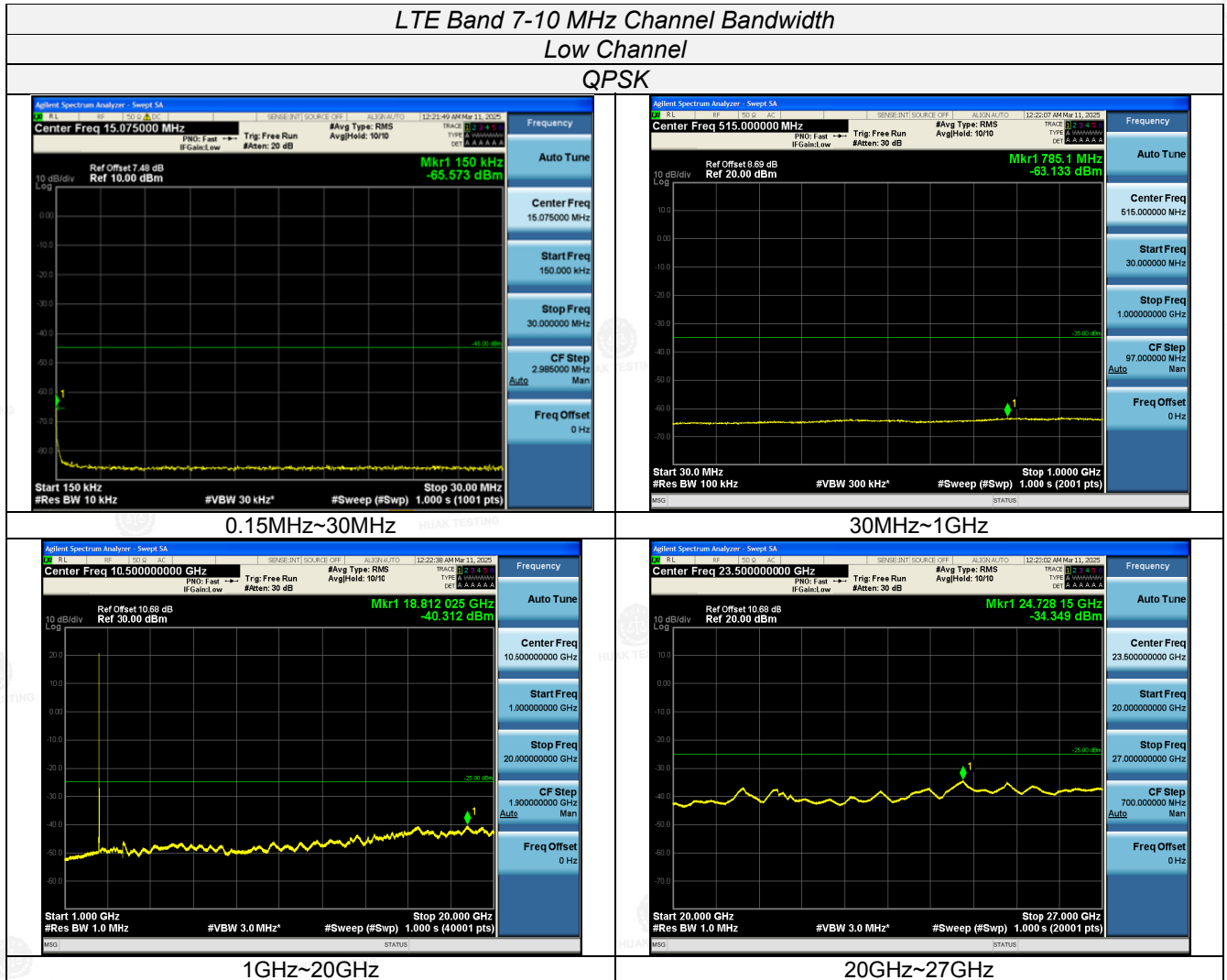
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LTE Band 7-5 MHz Channel Bandwidth
High Channel

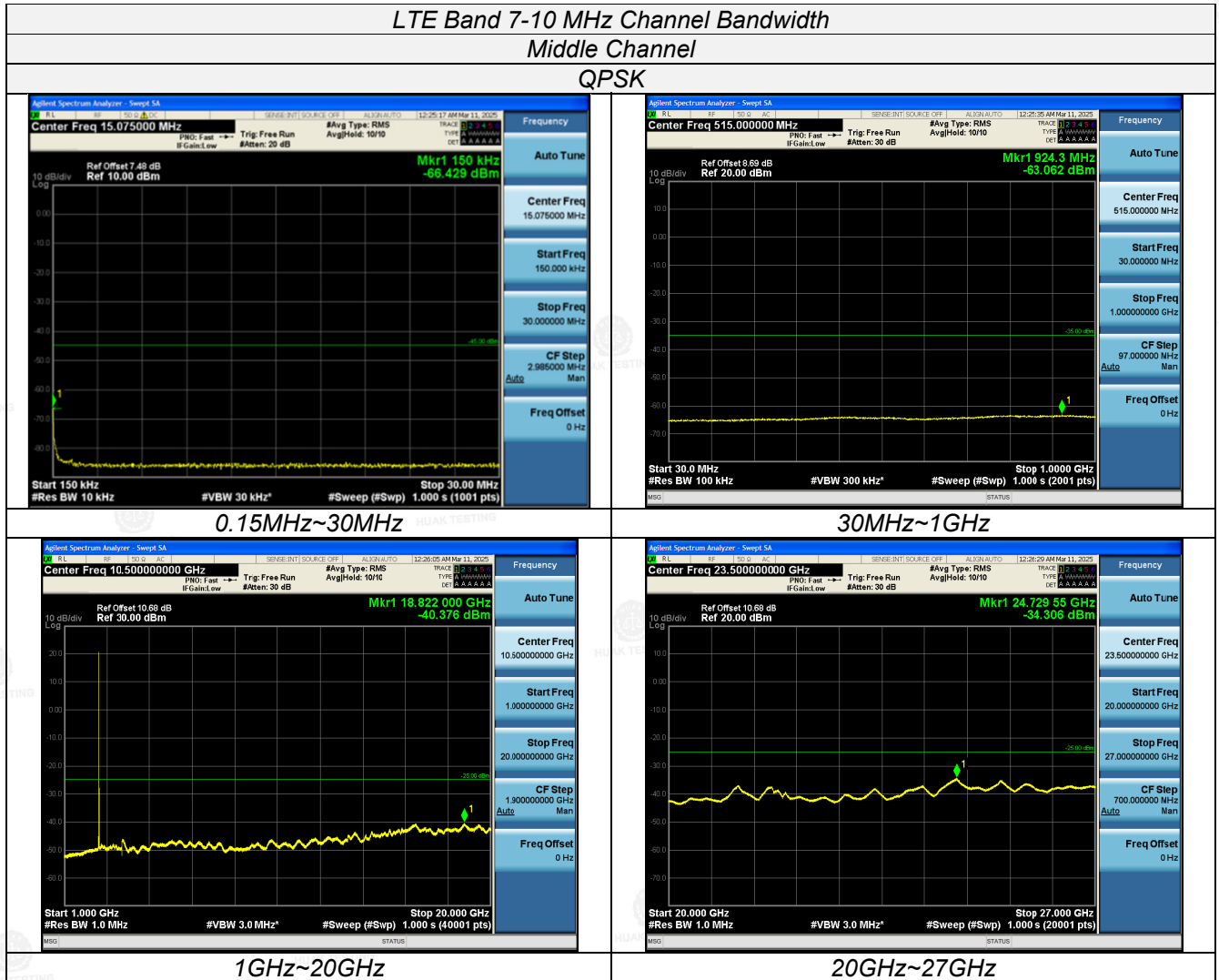
QPSK



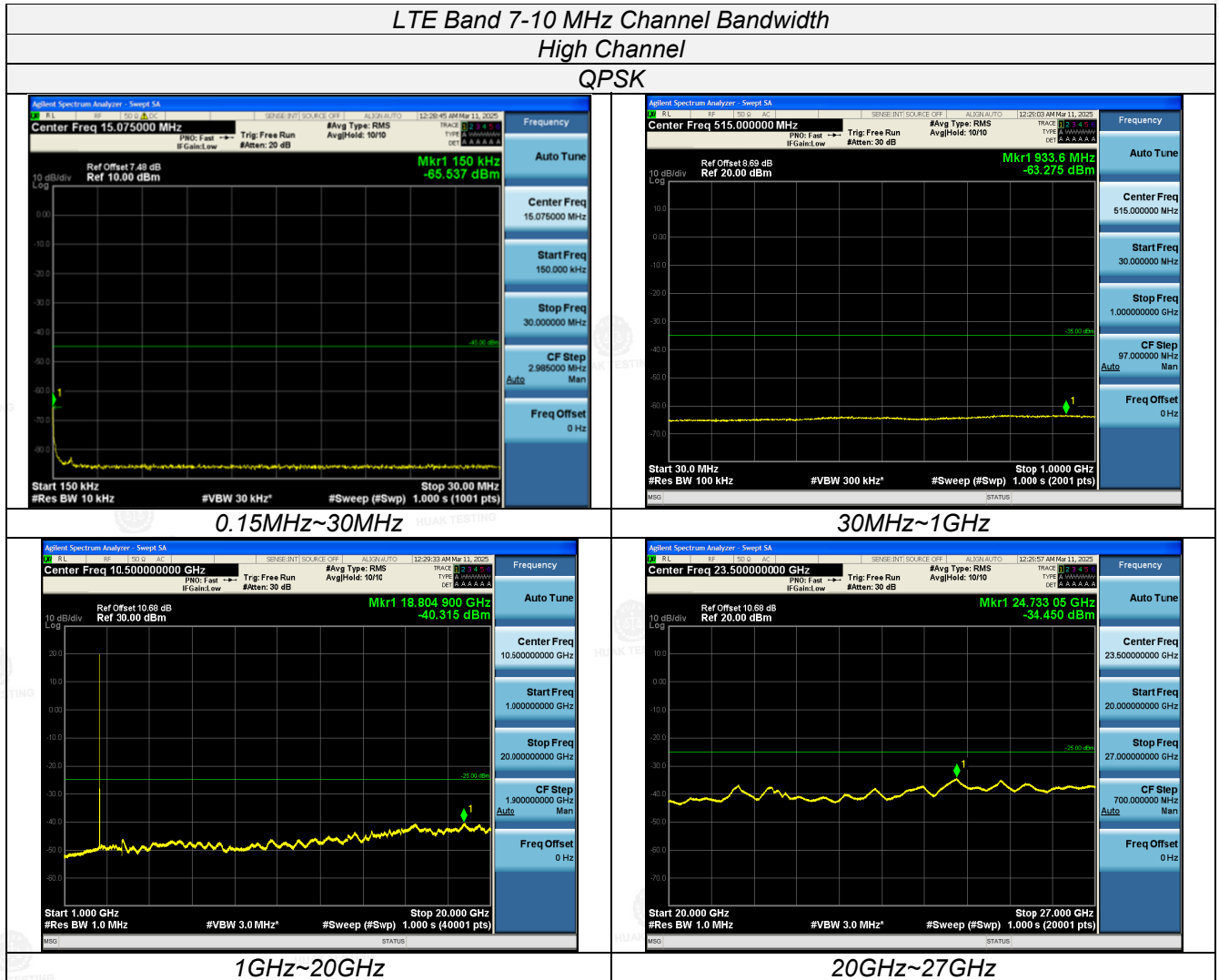
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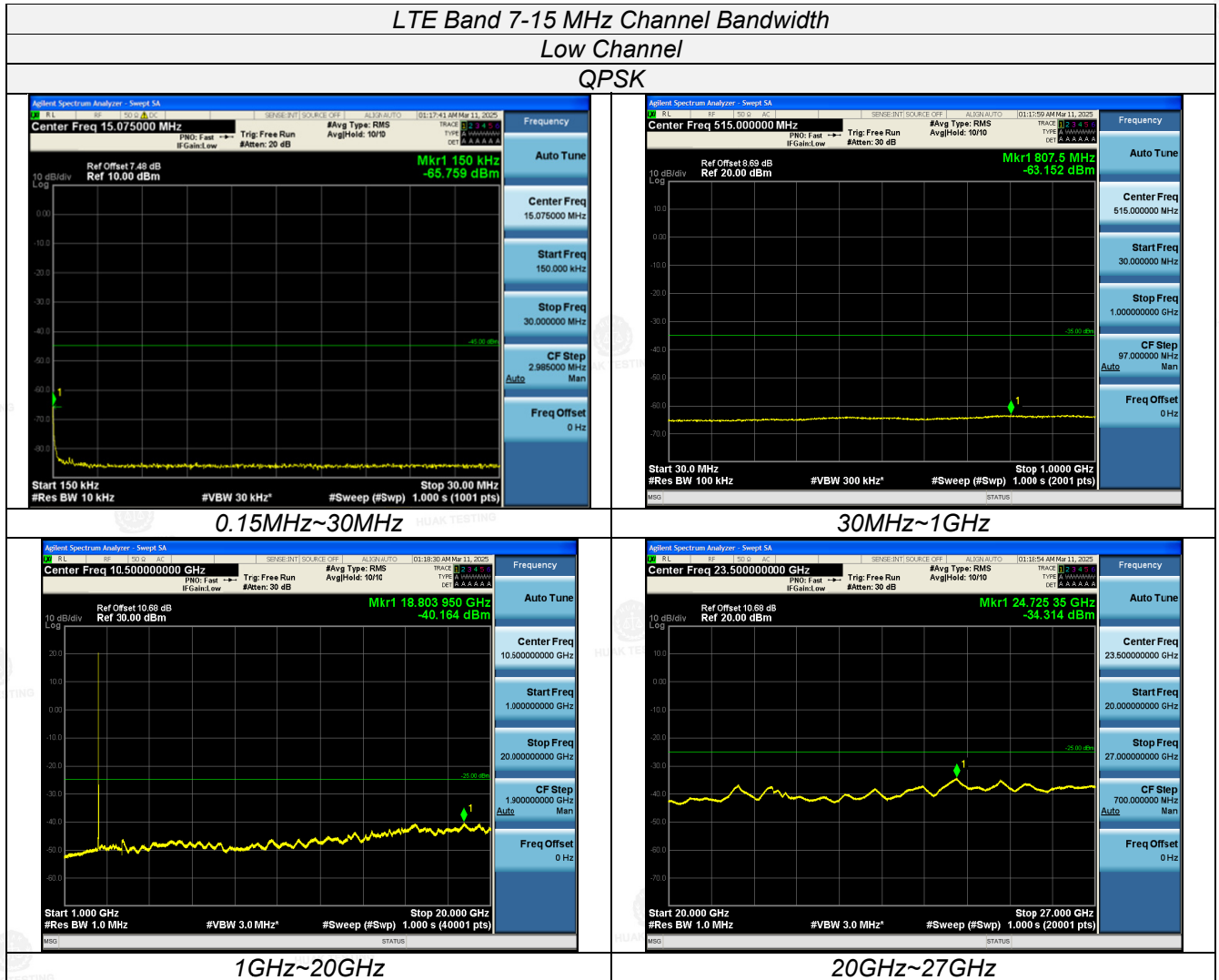
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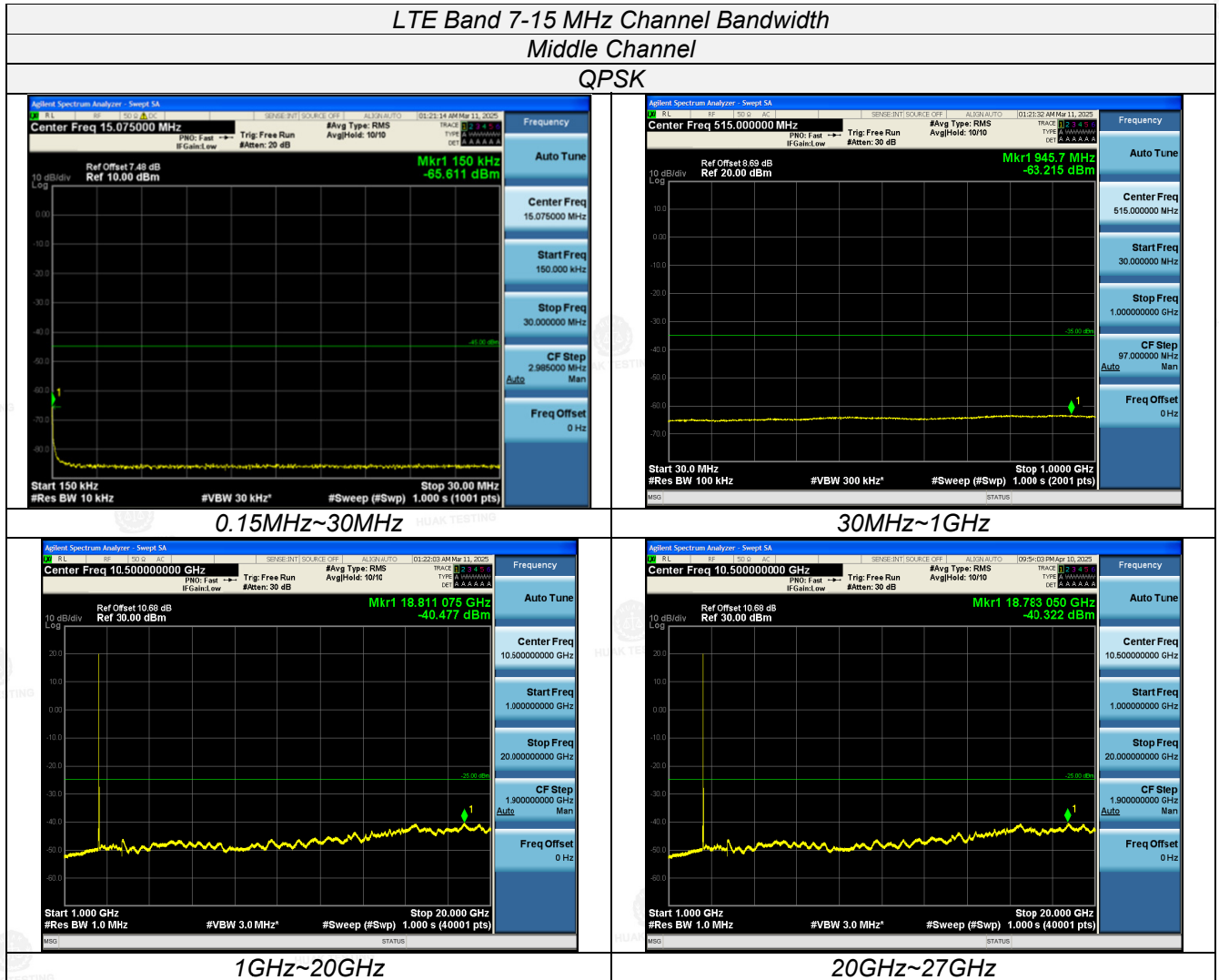
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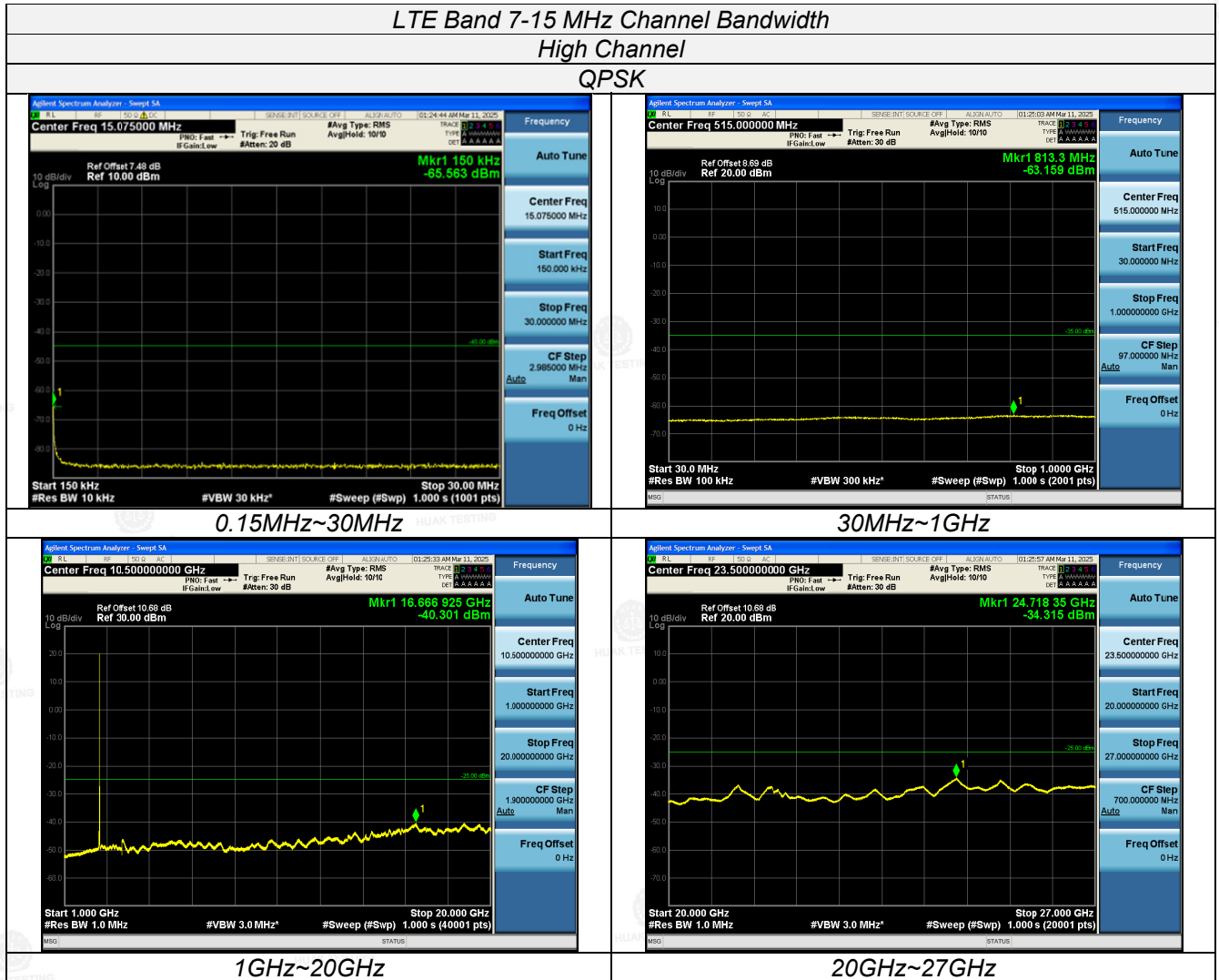
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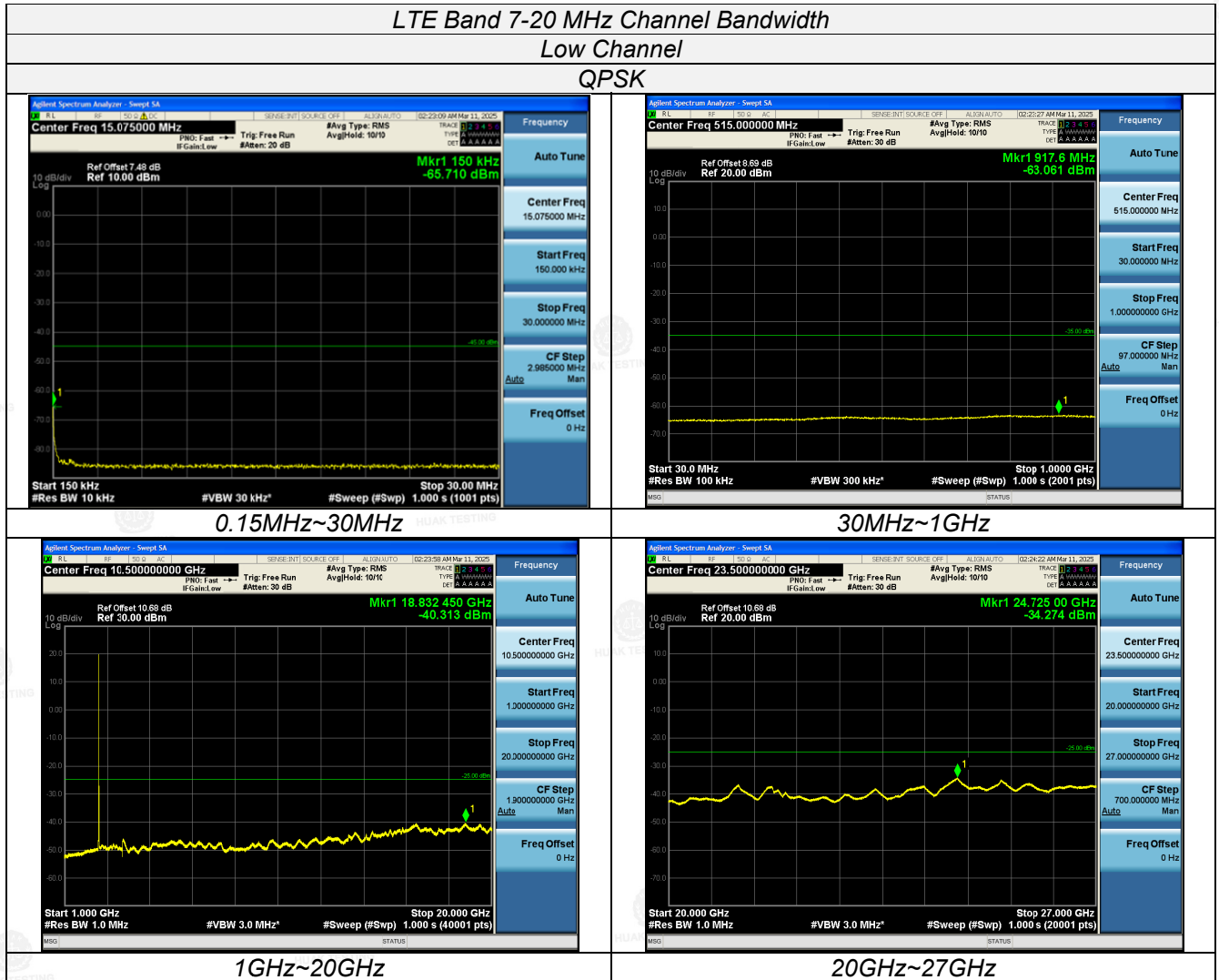
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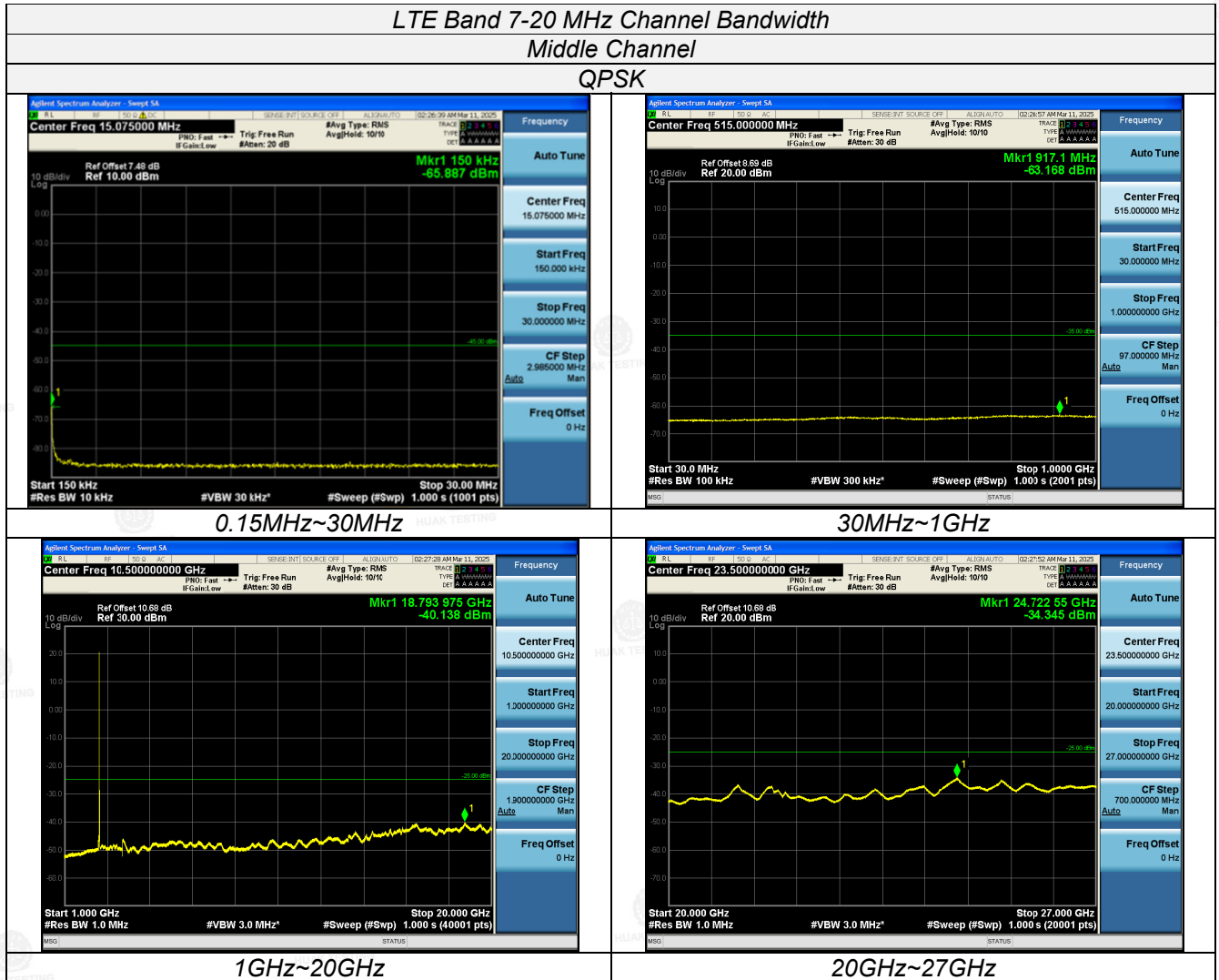


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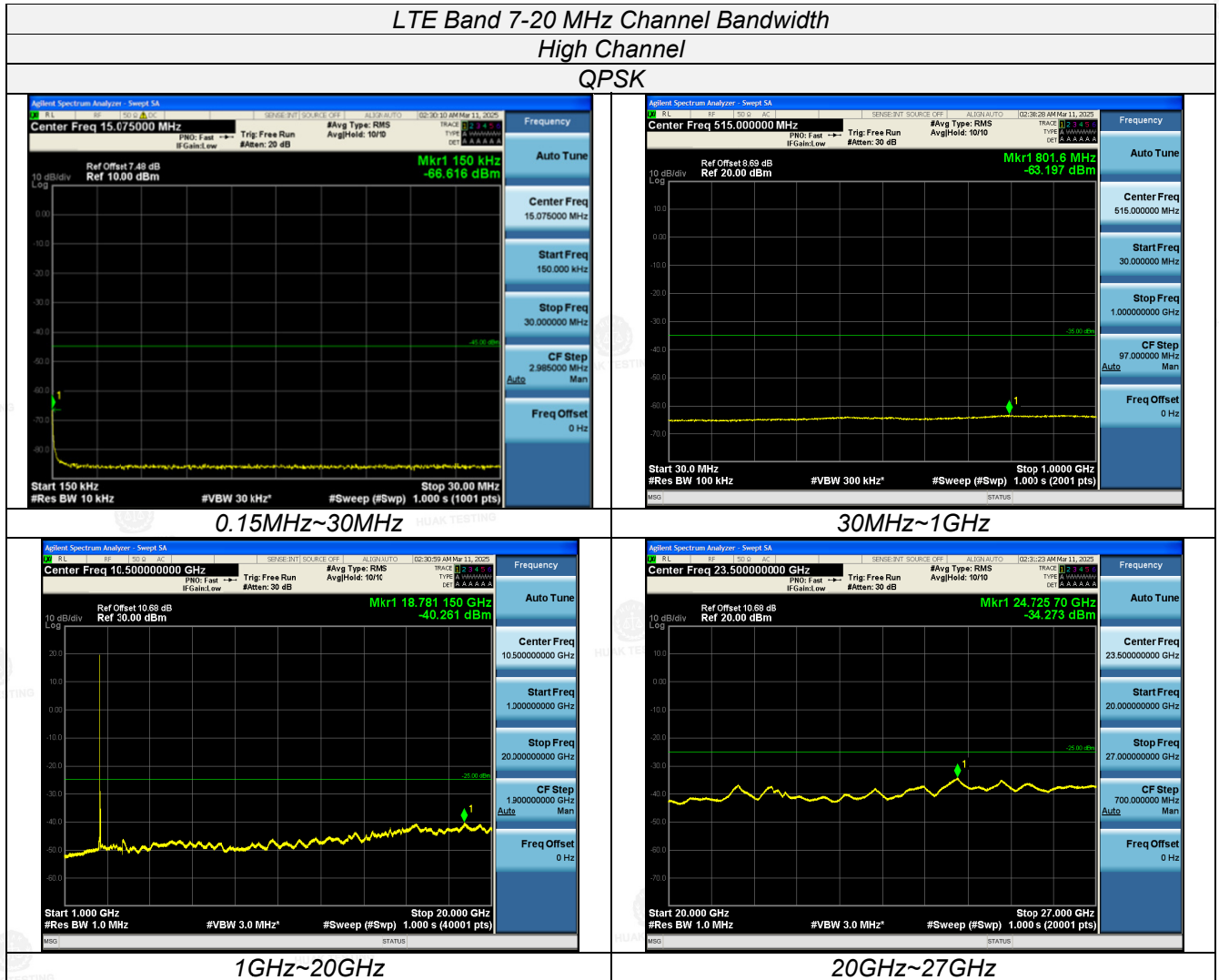
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